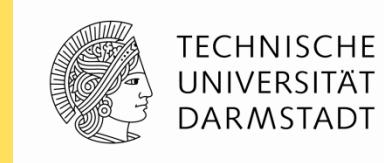


# Surfaces and Interfaces of Transparent Conducting Oxides

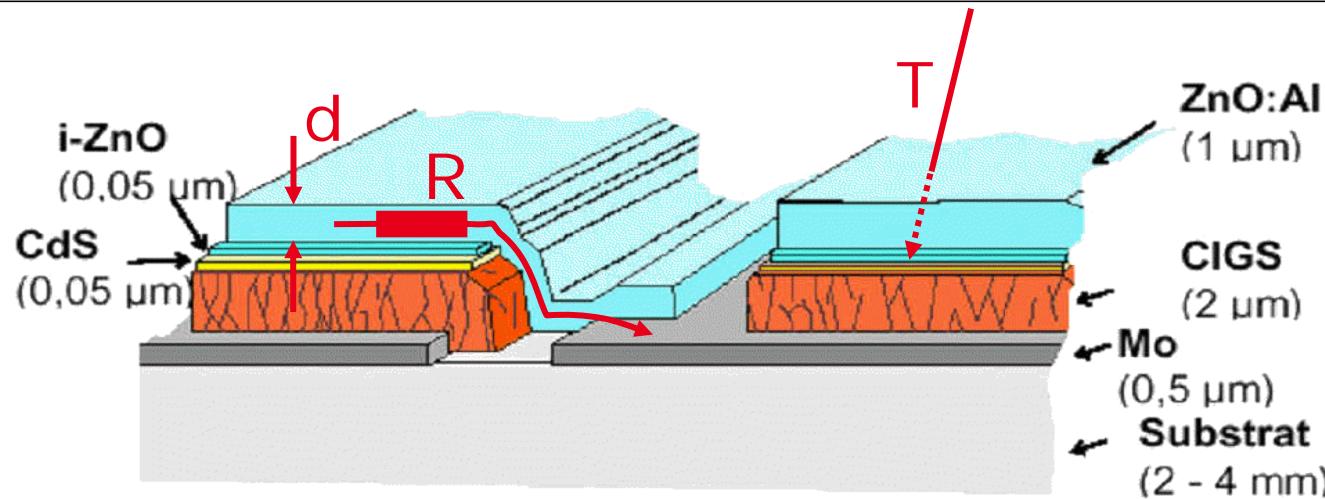


**Andreas Klein**

*Technische Universität Darmstadt, Institute of Materials Science, Surface Science Division*



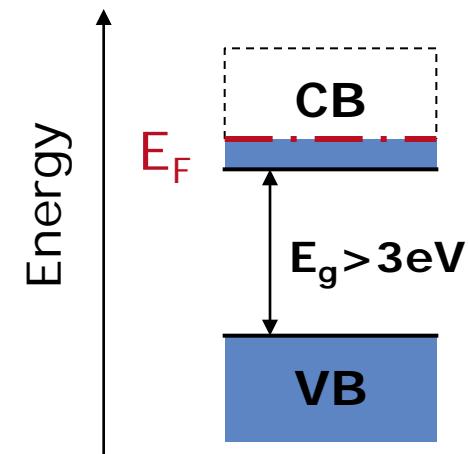
# Transparent conducting oxides



- high electrical conductivity ( $>10^3 \text{ } / \Omega\text{cm}$ )
- high optical transparency ( $>80\%$ )
- high infrared reflectivity

## Realization:

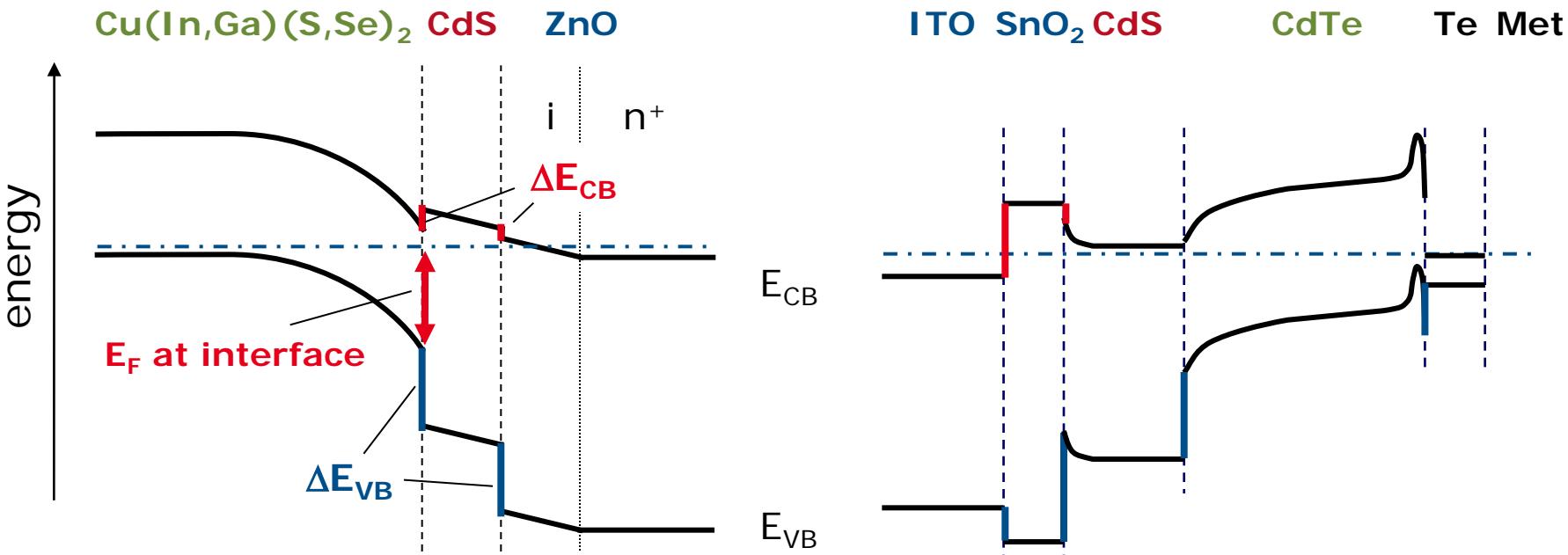
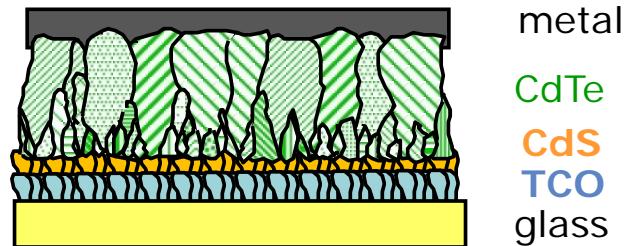
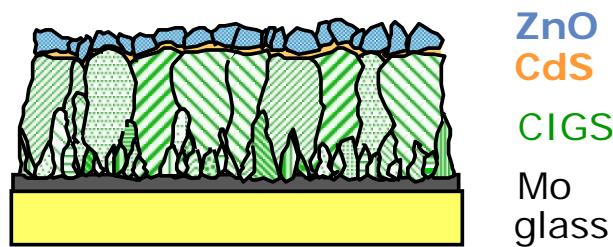
**Degenerately doped oxides (d<sup>10</sup>-systems)**  
**(ZnO, In<sub>2</sub>O<sub>3</sub>, SnO<sub>2</sub>, CdO and mixed oxides)**



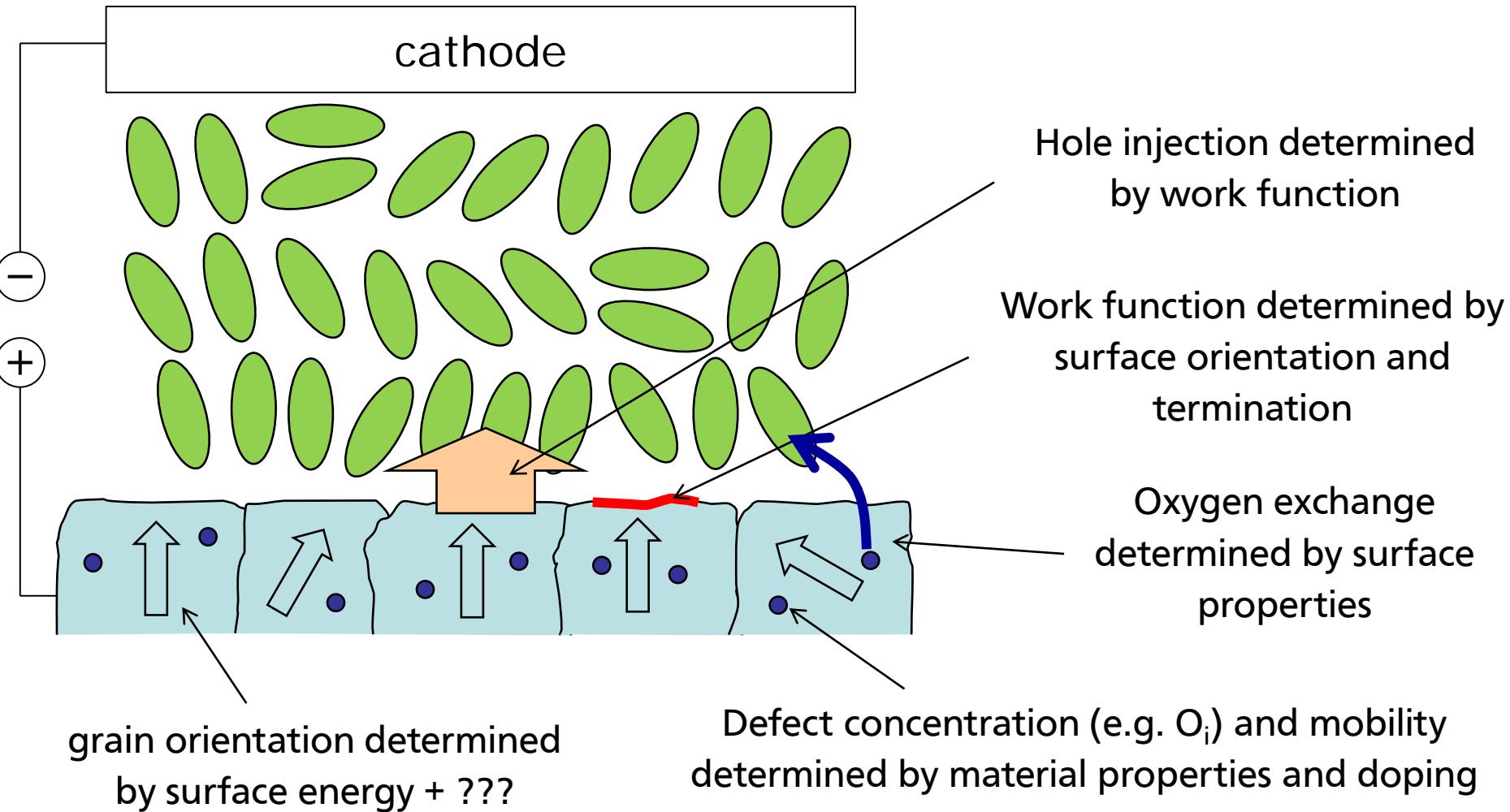
# Thin film solar cells



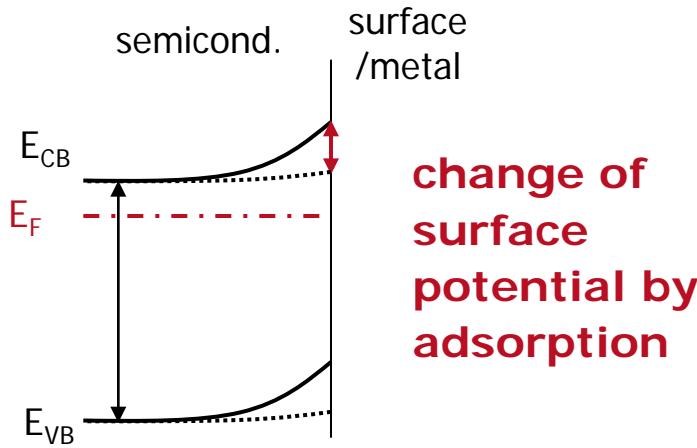
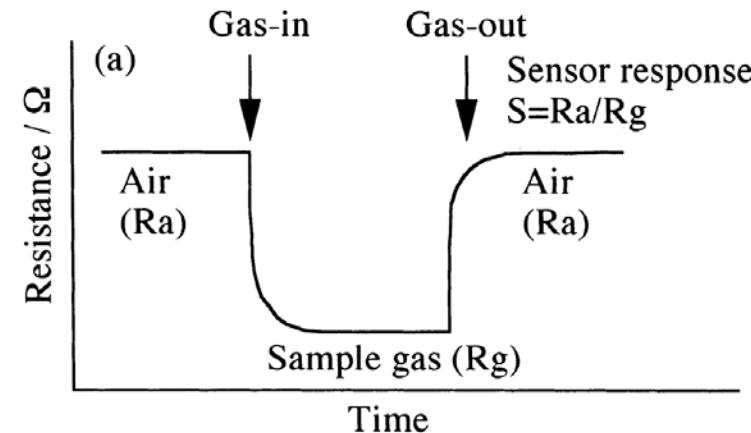
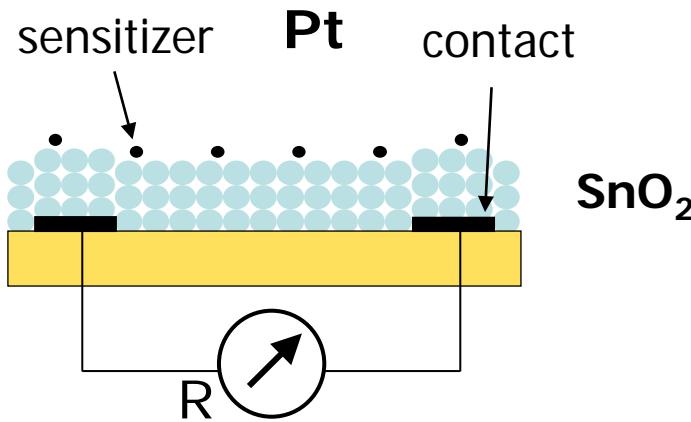
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# The TCO electrode in OLEDs



# Chemical gas sensors



- Sensor response explained by surface potential changes (ionosorption model)
- Changes of  $\text{SnO}_2$  bulk doping, (e.g. changes in  $[V_O]$ ) neglected

# Issues of TCO surfaces and interfaces



- **Surface properties**
  - **Workfunction of TCOs**
  - **Oxygen Exchange at TCO surfaces**
- **Interfaces Properties**
  - **Reactivity of interfaces**
  - **Energy level alignment (barrier heights)**

TCO oxide surfaces and interfaces are considerably more complex than those of conventional semiconductors



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# defect properties

# Defects in semiconductors

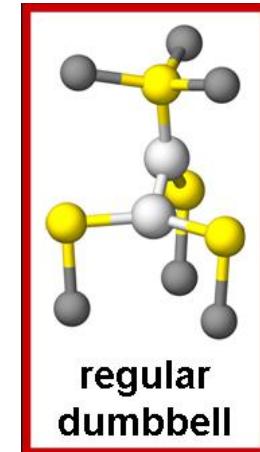


- Vacancies ( $V_{\text{cation}}$  (acceptor),  $V_{\text{anion}}$  (donor) )
- Interstitials ( $\text{Cat}_i$  (donor),  $\text{An}_i$  (acceptor) )
- Antisite defects (e.g.  $\text{Ga}_{\text{As}}$  and  $\text{As}_{\text{Ga}}$  in GaAs )
- Schottky defect pair ( $V_{\text{cat}} + V_{\text{an}}$ ), ( $\text{Cat}_i + \text{An}_i$ )
- Frenkel defect pair ( $V_{\text{cat}} + \text{Cat}_i$ ), ( $V_{\text{an}} + \text{An}_i$ )
- F-centers (vacancy + e, h)
- Polarons
- Electrons and holes
- Impurities (substitutional, interstitial)

**defect concentration**     $N_d \approx N \cdot \exp\left(-\frac{\Delta h_d}{k_B T}\right)$

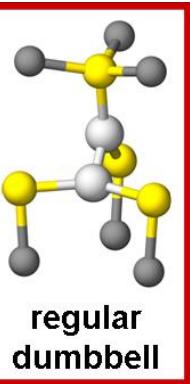
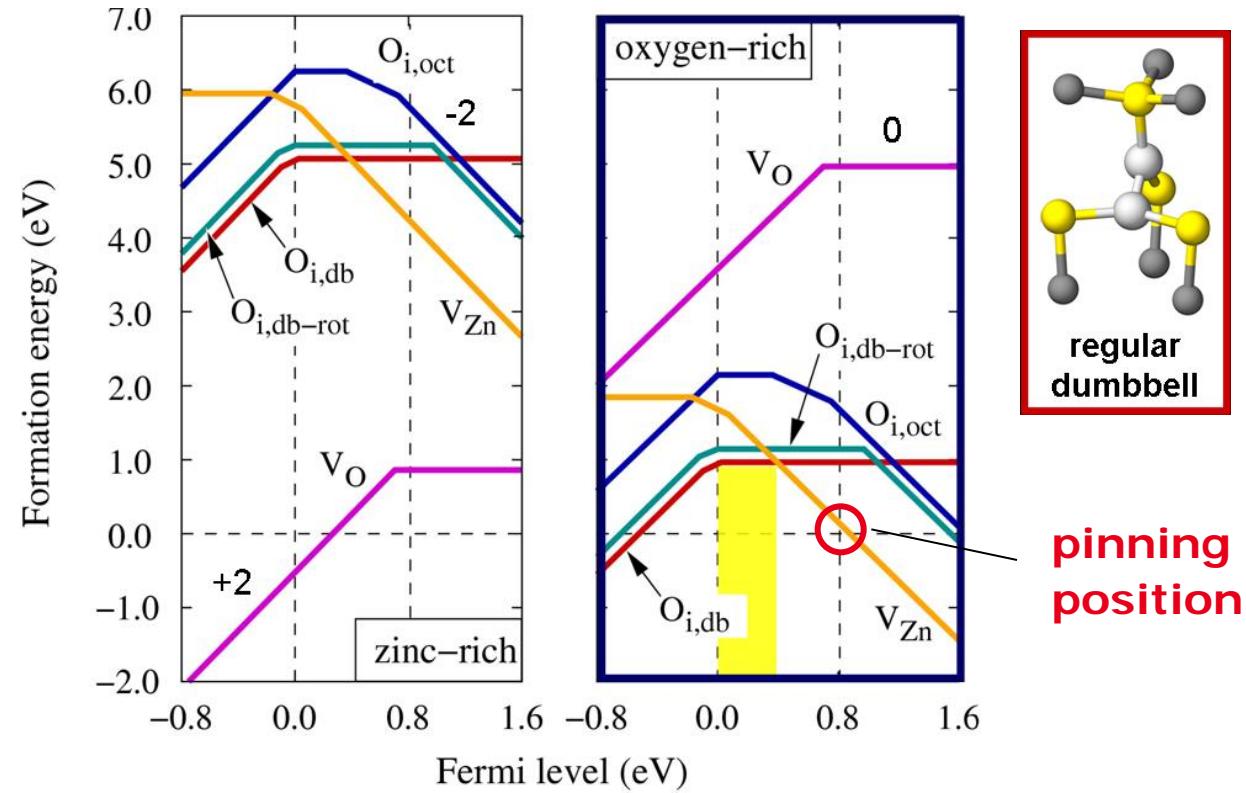
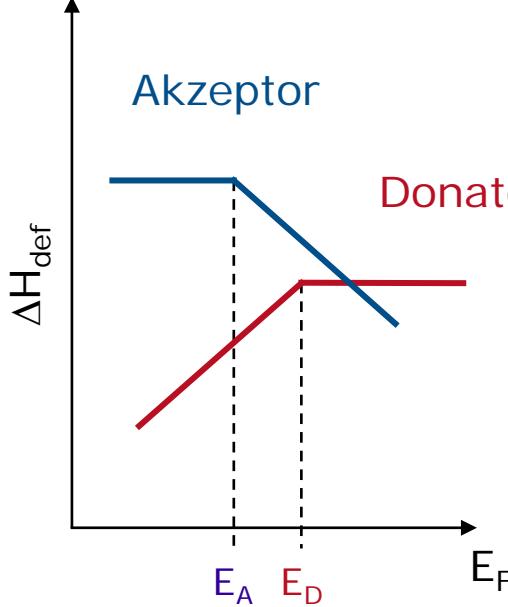
} not stoichiometric,  
charged

} stoichiometric,  
uncharged



regular  
dumbbell  
oxygen interstitial  
in ZnO

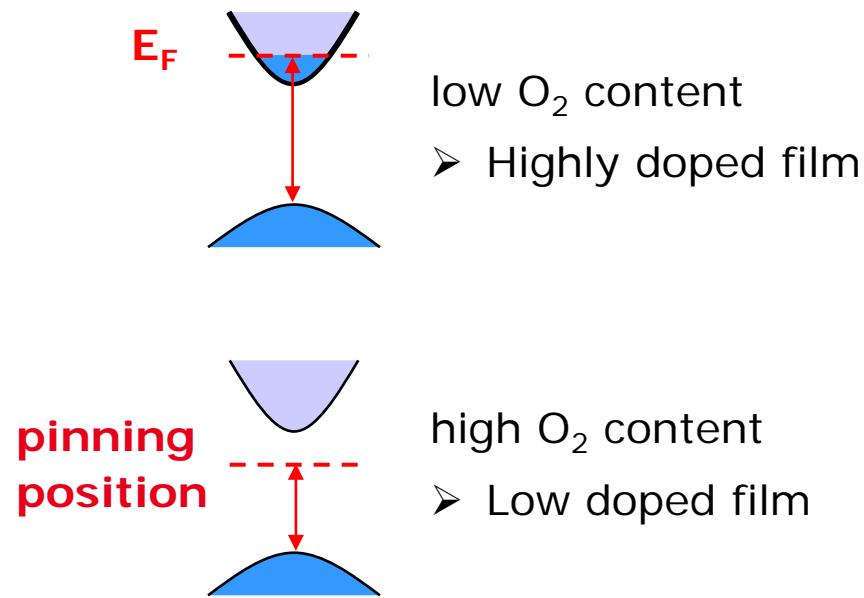
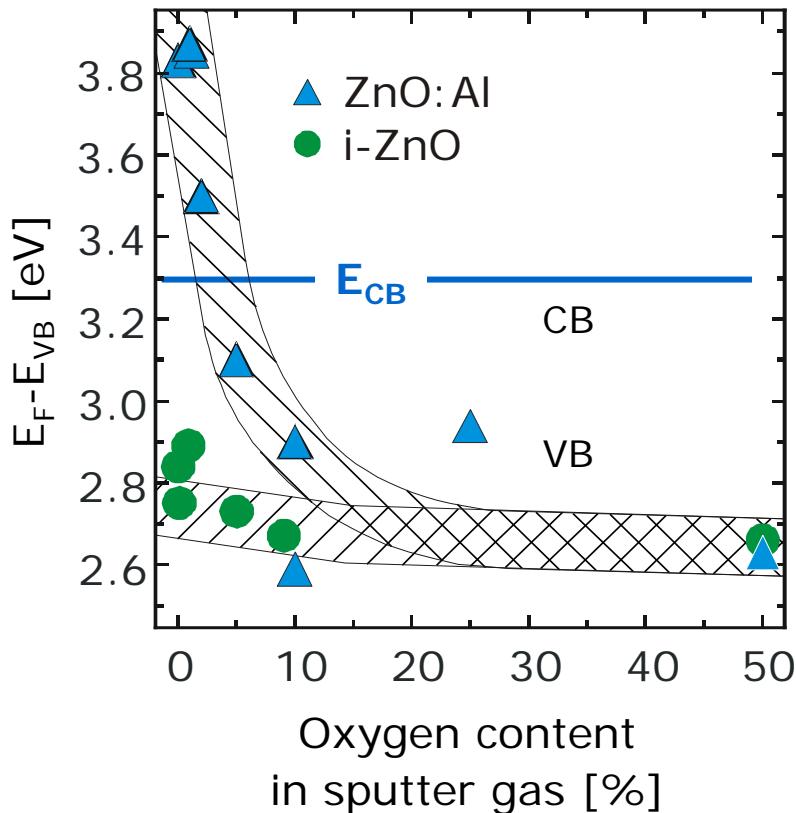
# ZnO – Defects



**pinning  
position**

➤ compensation of donors by Zinc-vacancies ( $V_{\text{Zn}}$ )  
under oxygen rich conditions

# ZnO – Fermi level

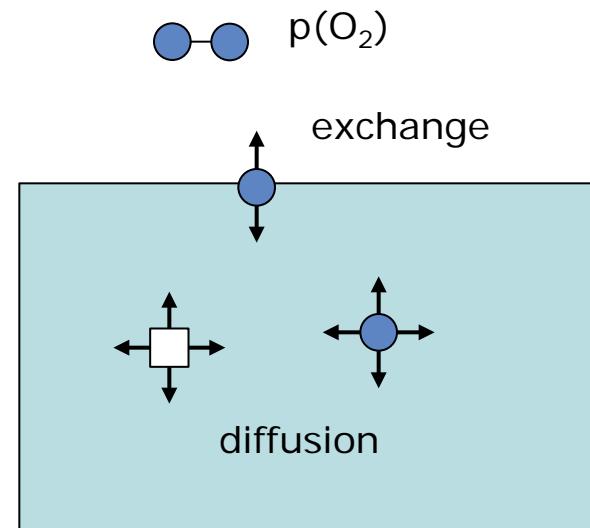


- Change of doping with pO<sub>2</sub>
- Pinning by Zn-vacancies

# Intrinsic defects of TCOs



| material             | defects                   |
|----------------------|---------------------------|
| ZnO                  | $V_{Zn}$ , $Zn_i$ , $V_O$ |
| ZnO:Al               | $Al_{Zn}$ , $V_{Zn}$      |
| Indium Oxide         | $V_O$                     |
| Indium Oxide:Sn      | $Sn_{In}$ , $O_i$         |
| SnO <sub>2</sub>     | $V_O$                     |
| SnO <sub>2</sub> :Sb | $Sb_{Sn}$ , ??            |



- Conductivity determined by doping and intrinsic defects (Stoichiometry)
- Changes of conductivity by changes of stoichiometry require oxygen exchange and diffusion



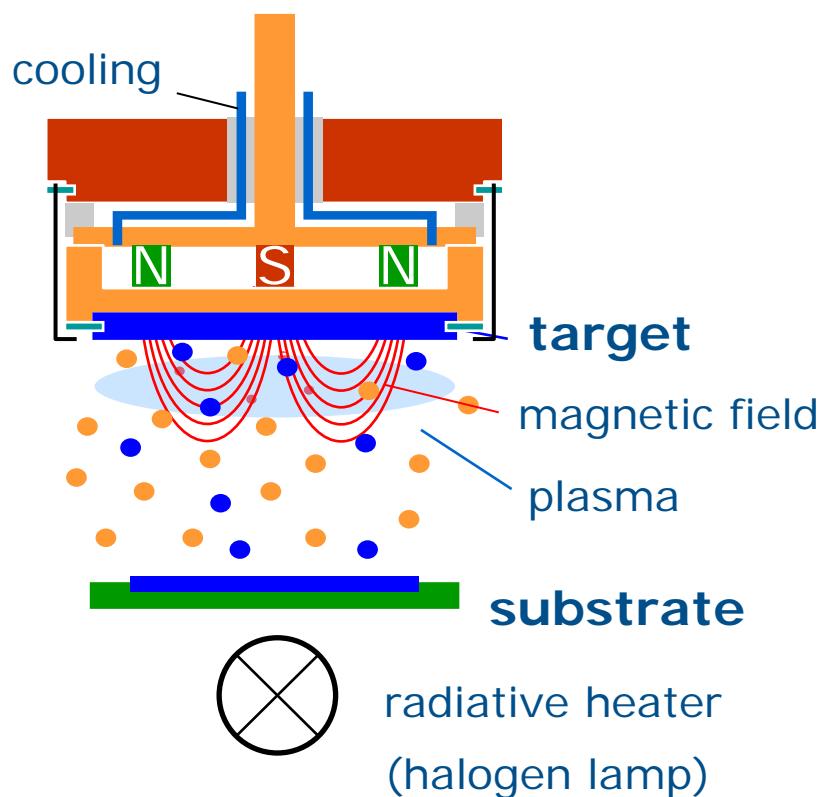
# **Assessment of surface and interface properties**

# Thin film deposition

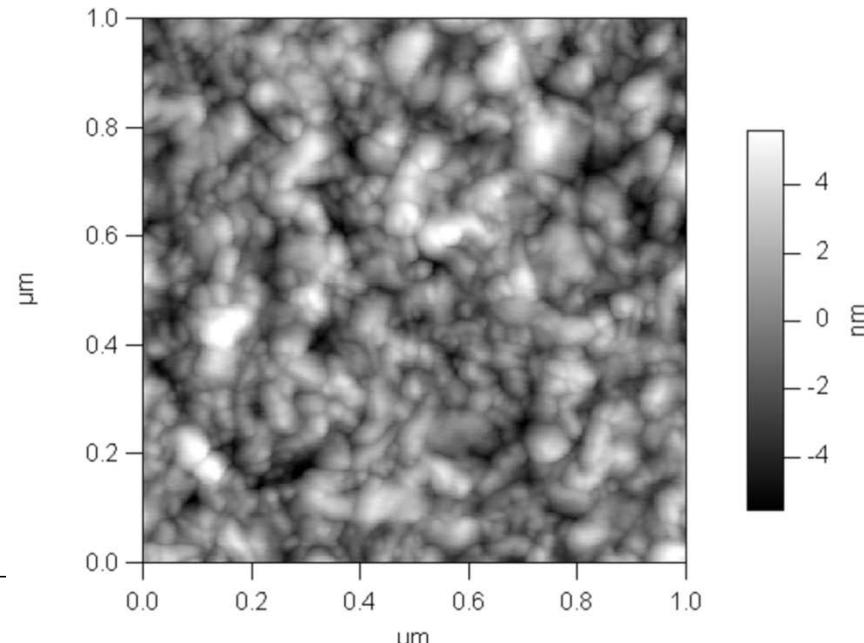


magnetron sputtering

RF/DC power



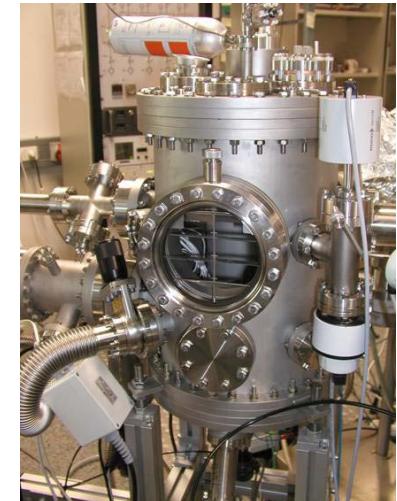
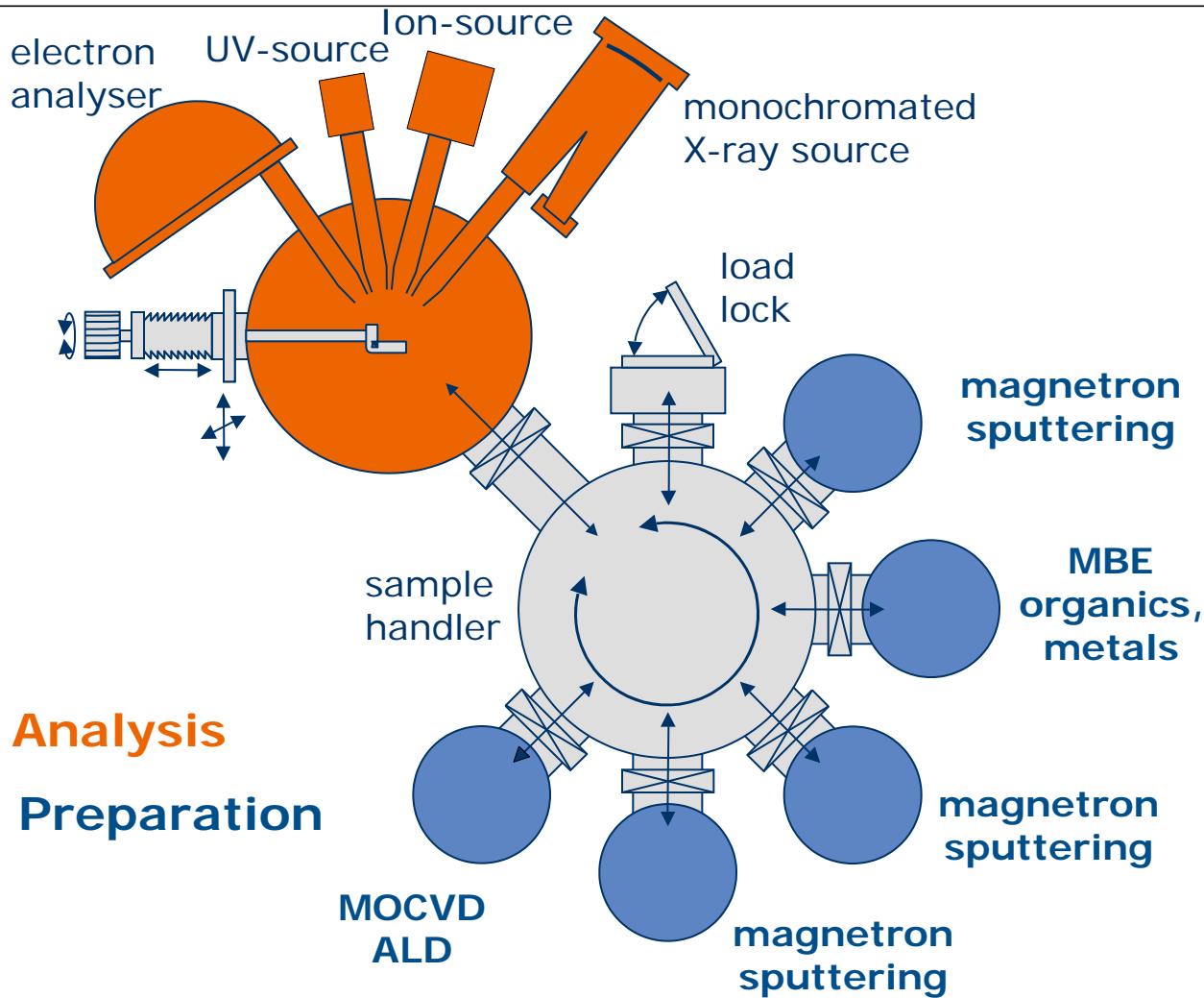
- ✓ Wide range of materials
- ✓ low substrate temperatures
- ✓ epitaxial growth possible
- ✓ wide range of parameter variation
- ✓ high deposition rates
- ✓ large area deposition



# Integrated System – DAISY-MAT



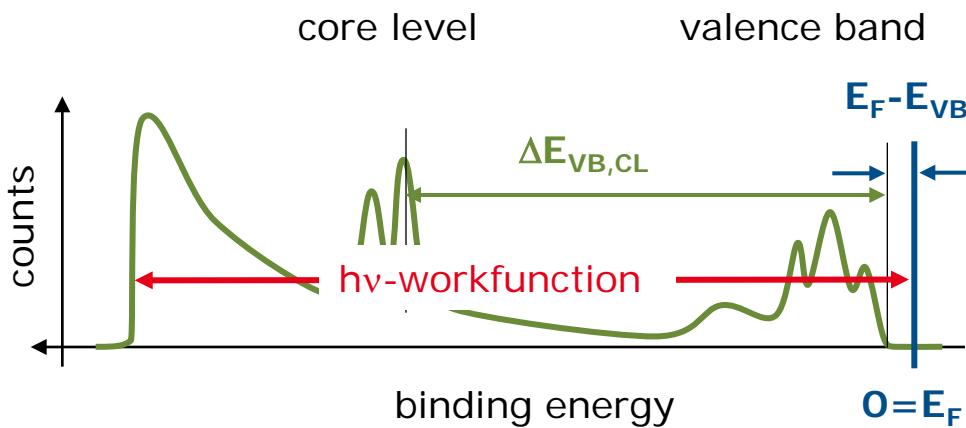
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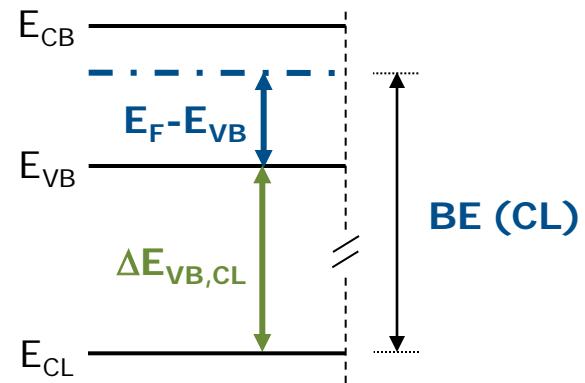
# Photoemission – Barrier Heights



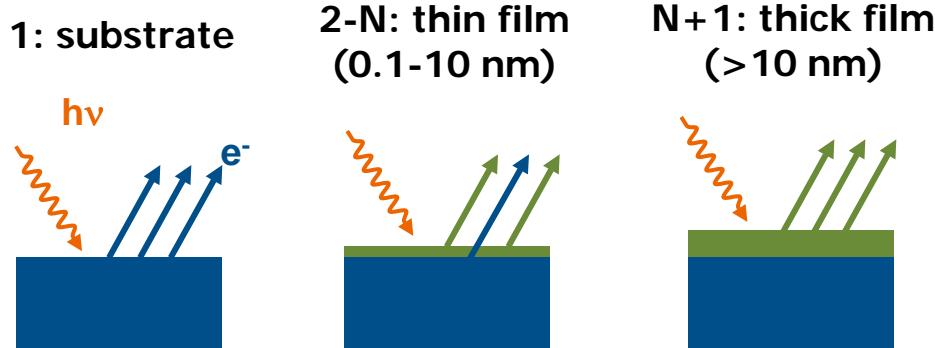
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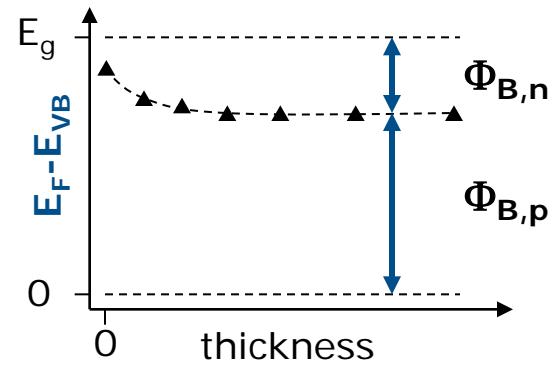
energy diagram



## Interface experiment



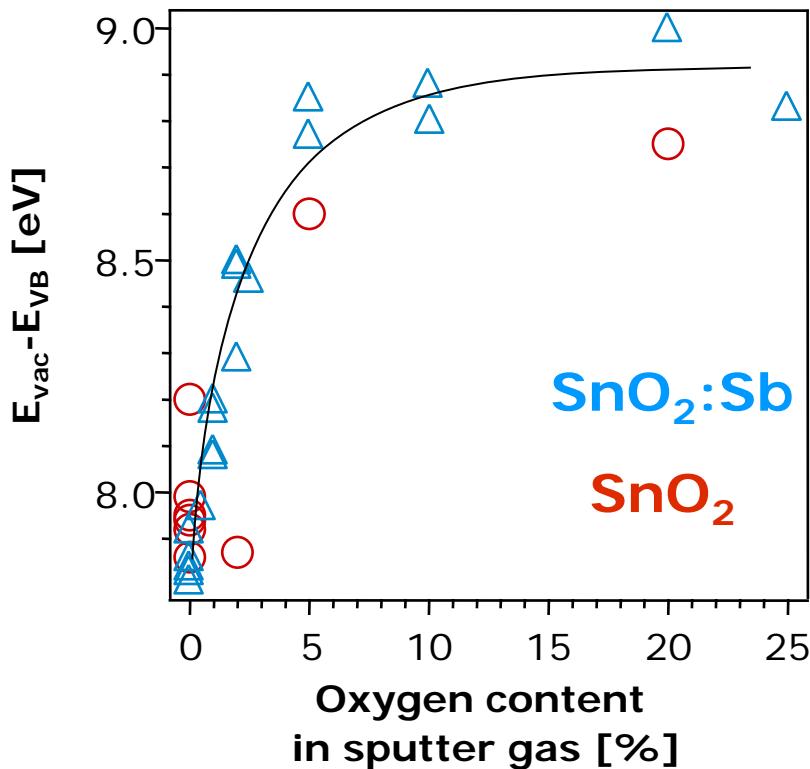
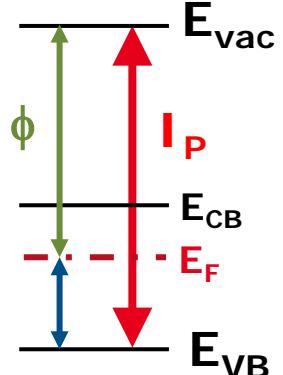
## Schottky barrier



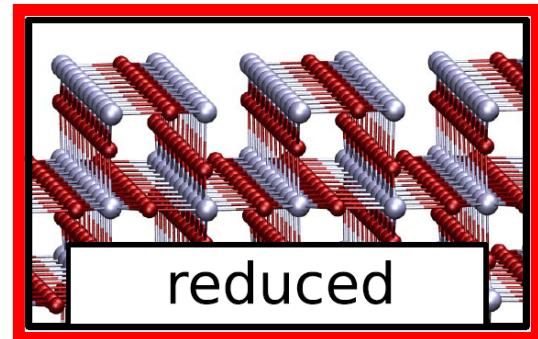


# **work functions of TCOs**

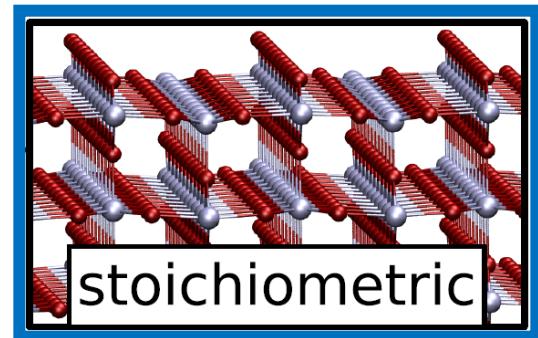
# $\text{SnO}_2$ – ionization potential



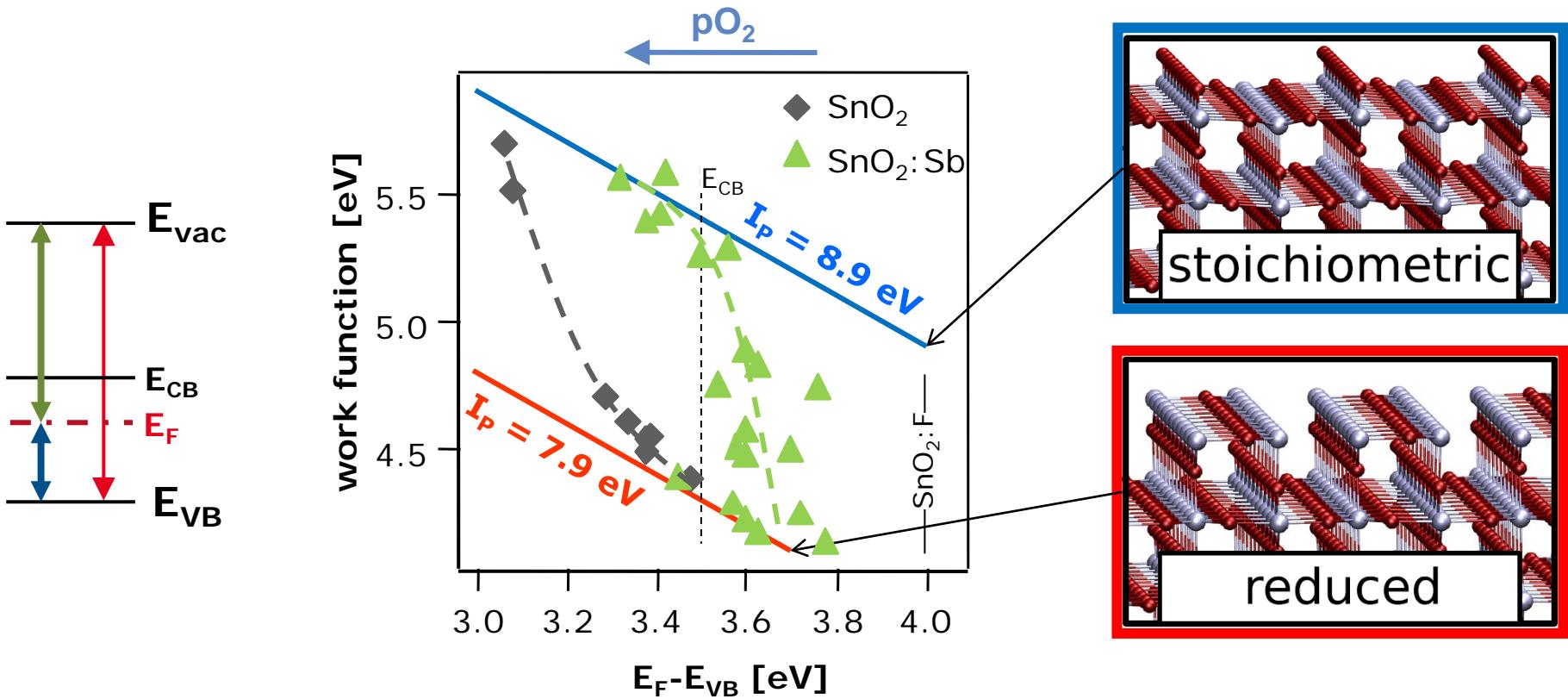
reduced (110) surface



oxidized “stoichiometric”  
(110) surface

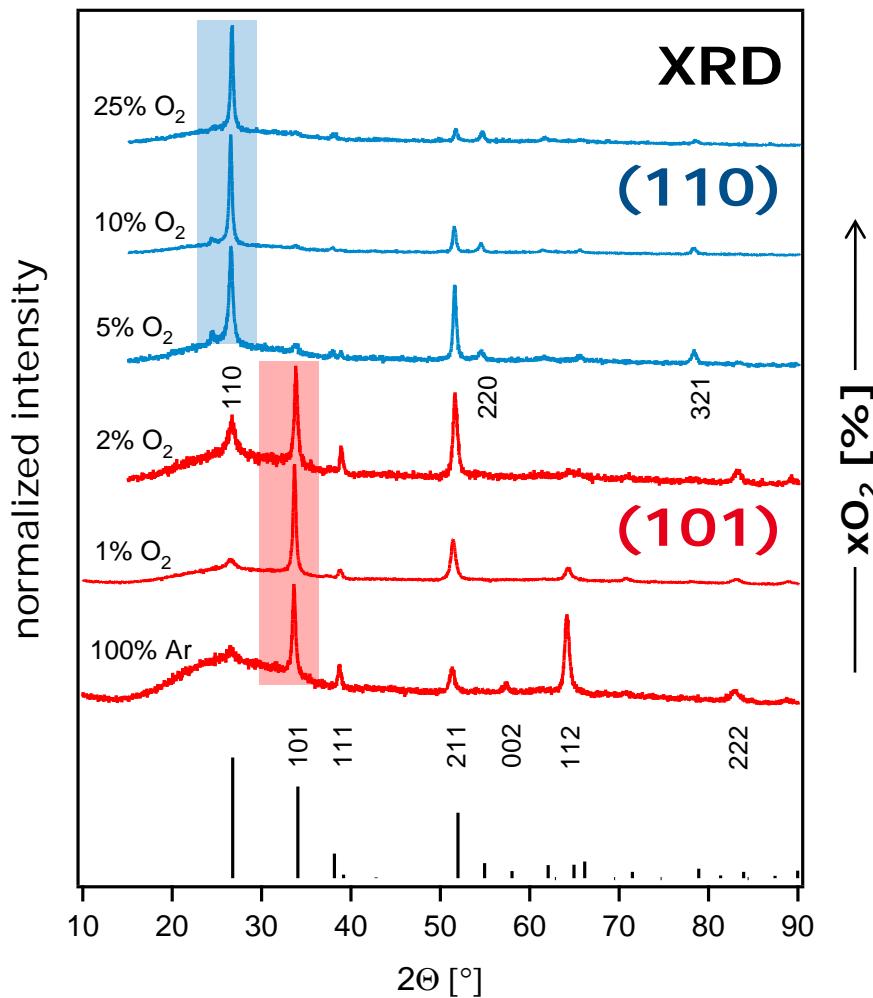
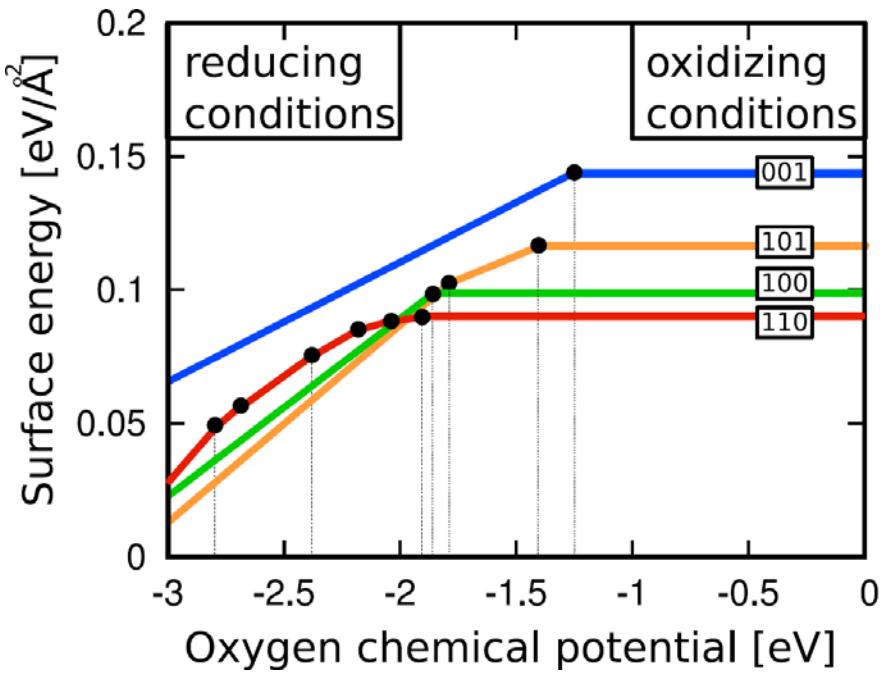


# $\text{SnO}_2$ – work function



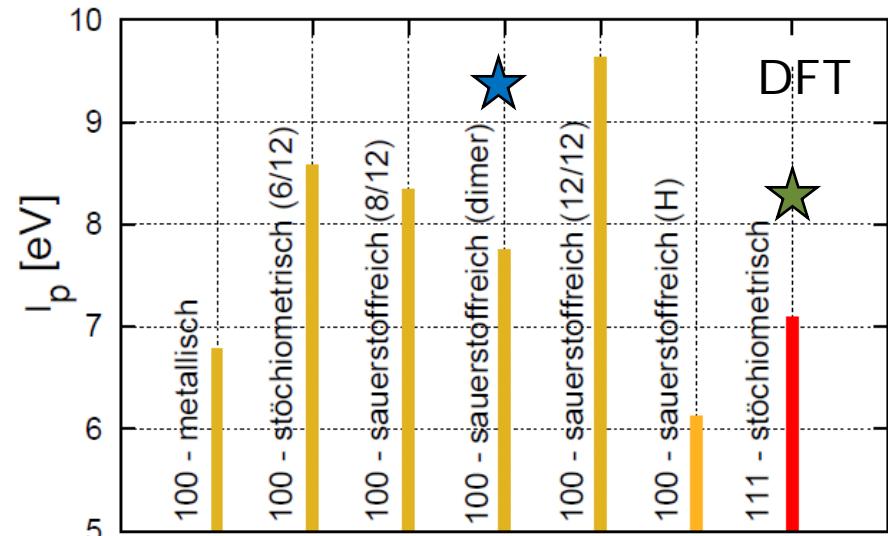
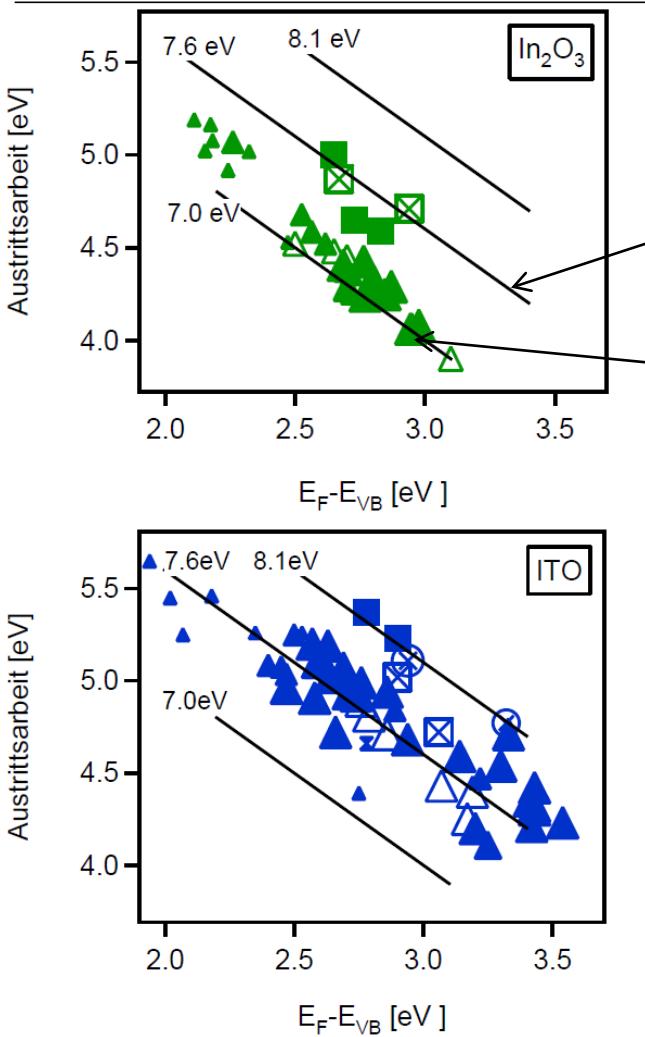
➤ Identification of surface termination by ionization potential

# $\text{SnO}_2$ – preferred orientation



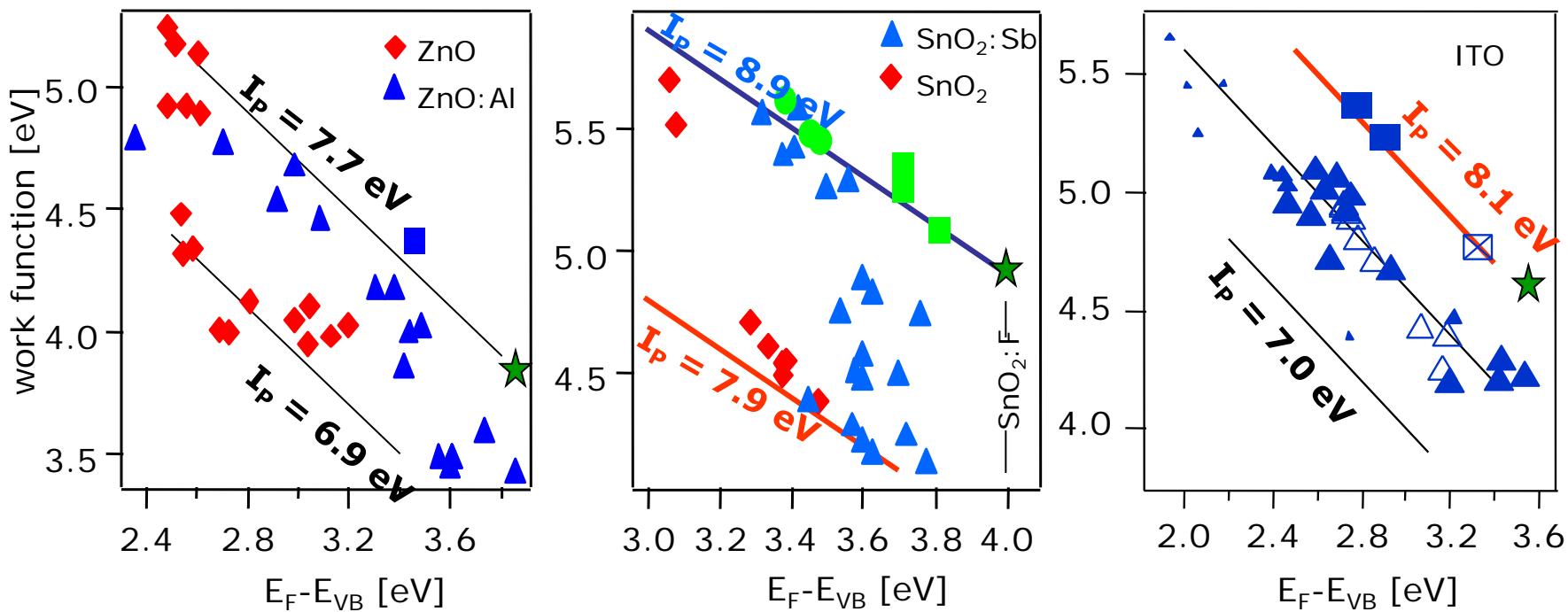
- Change of stable surface orientation with oxygen pressure

# Work function of $\text{In}_2\text{O}_3$ and ITO



- Almost no change of surface termination with oxygen
- Work function depends on surface orientation
- Differences between  $\text{In}_2\text{O}_3$  and ITO explained by texture of films
- Surface oxidation (e.g. via ozone) only possible for (100) orientation

# TCO work functions



➤ Large variation of work function

but  $\Delta E_{VB}$  does not depend on work function



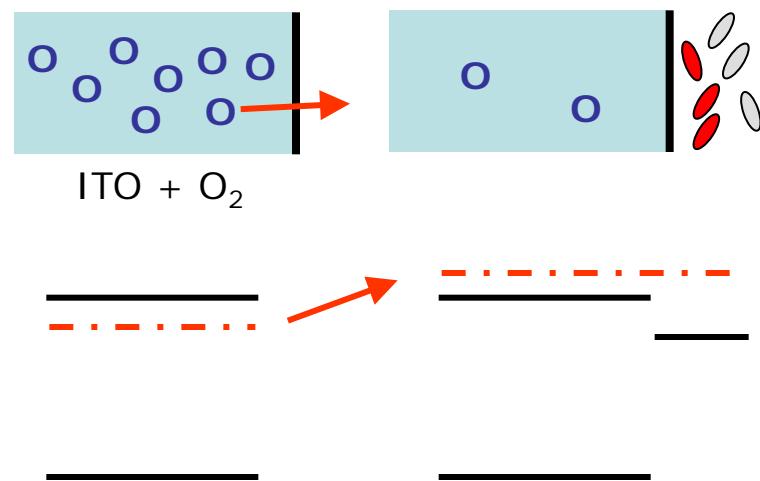
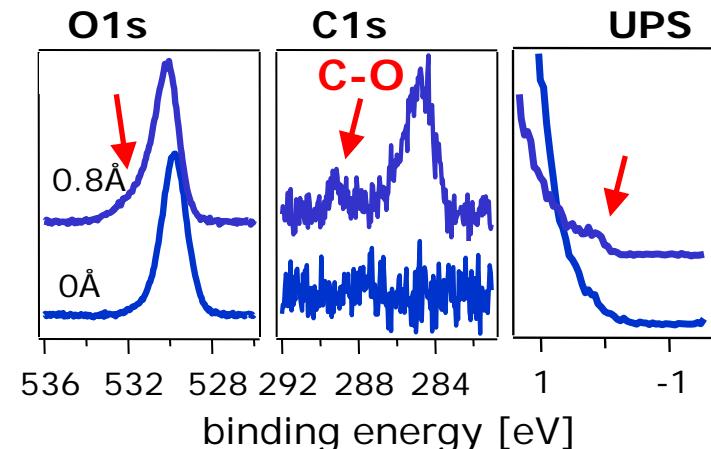
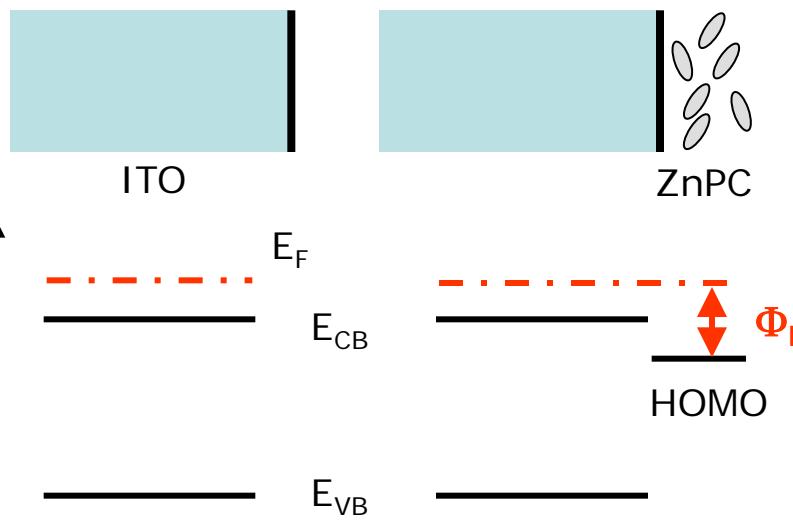
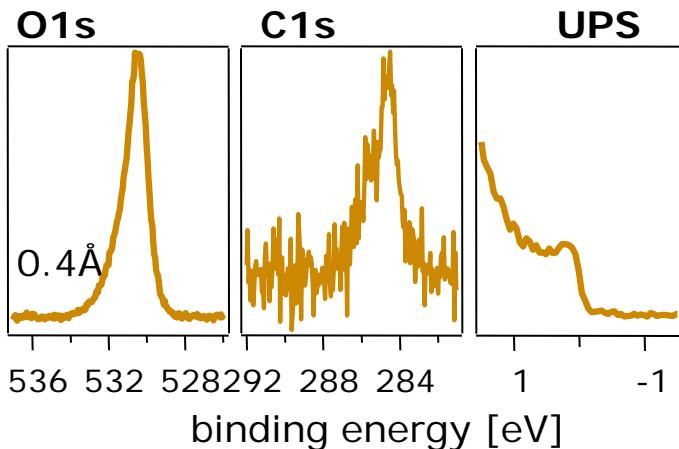
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# Oxygen Exchange

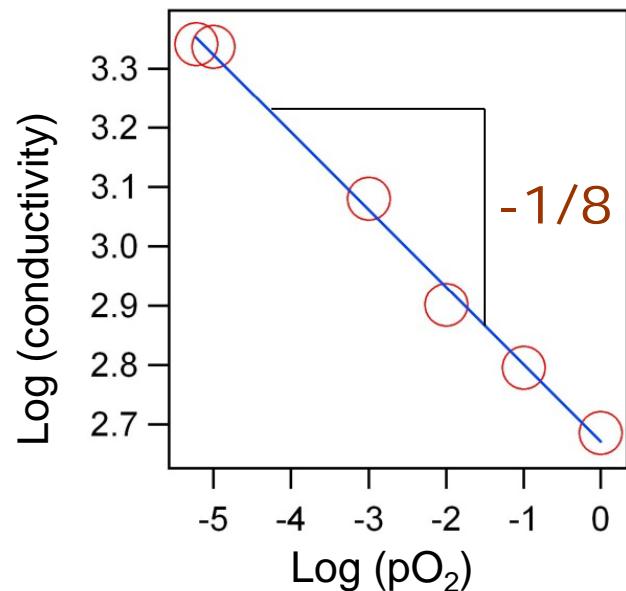
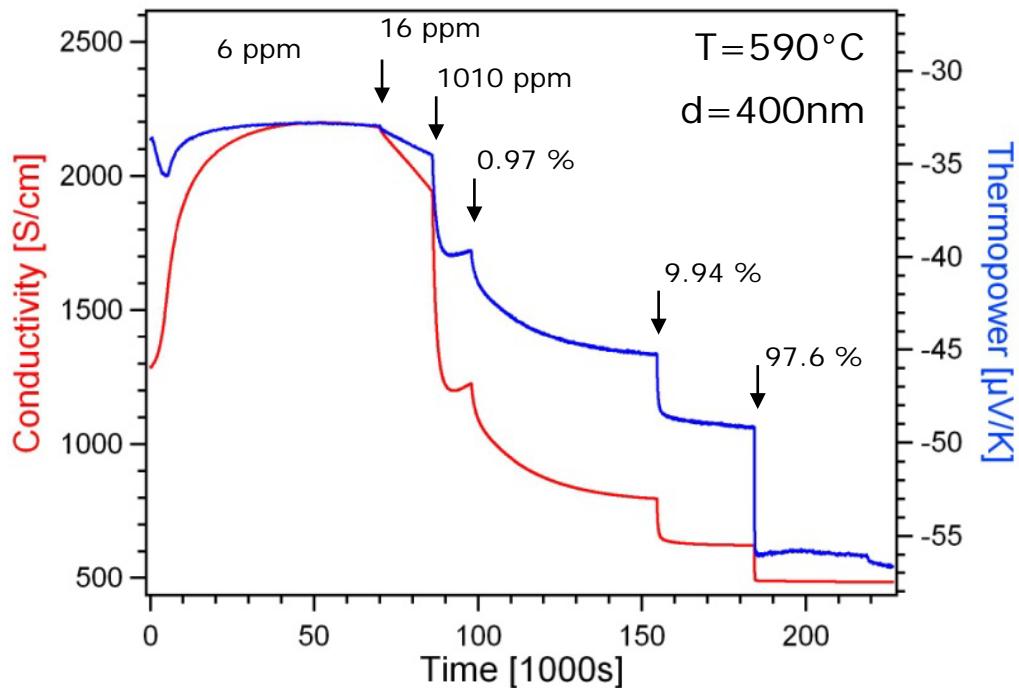
# ITO/organic interface



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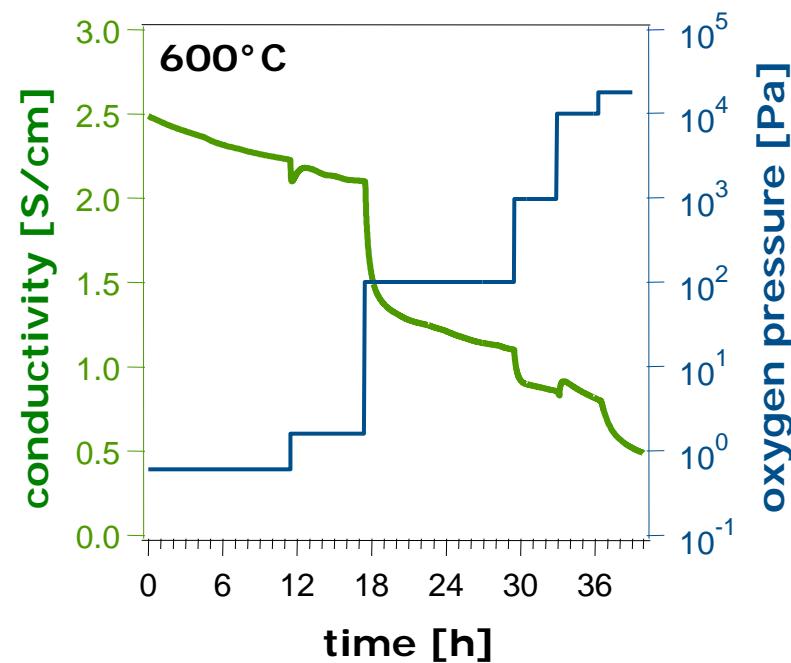
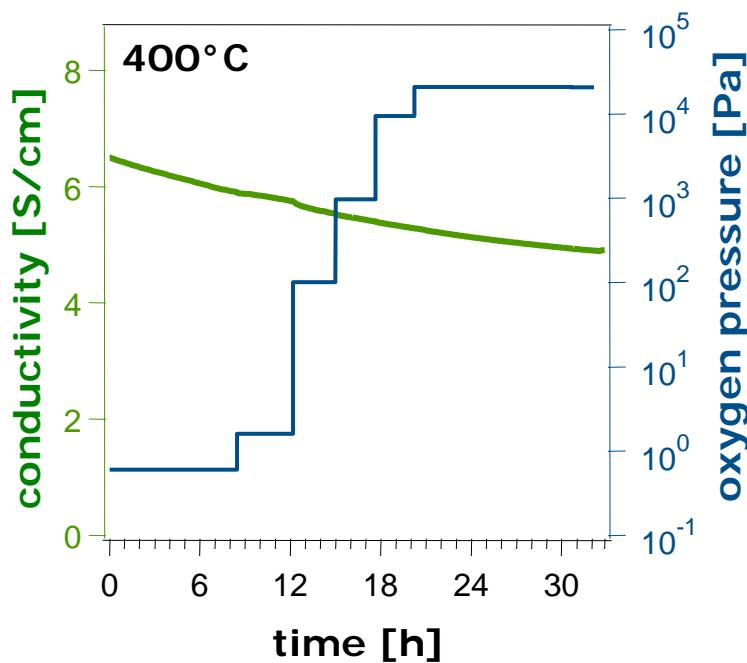


# Conductivity relaxation of ITO (1 bar)



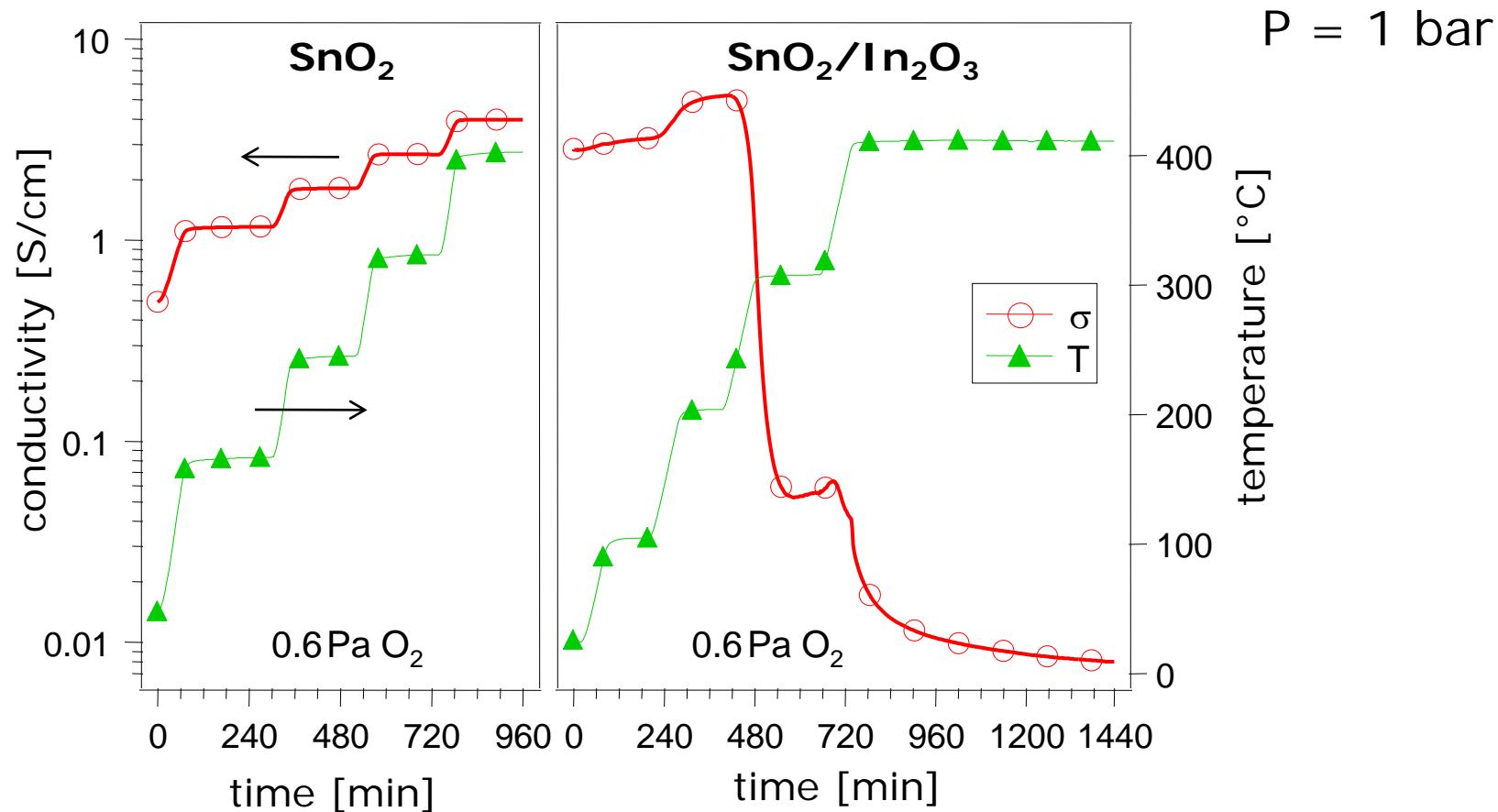
- Conductivity depends on oxygen pressure
- Slope related to dominant defect species

# Conductivity relaxation of $\text{SnO}_2$ (1 bar)



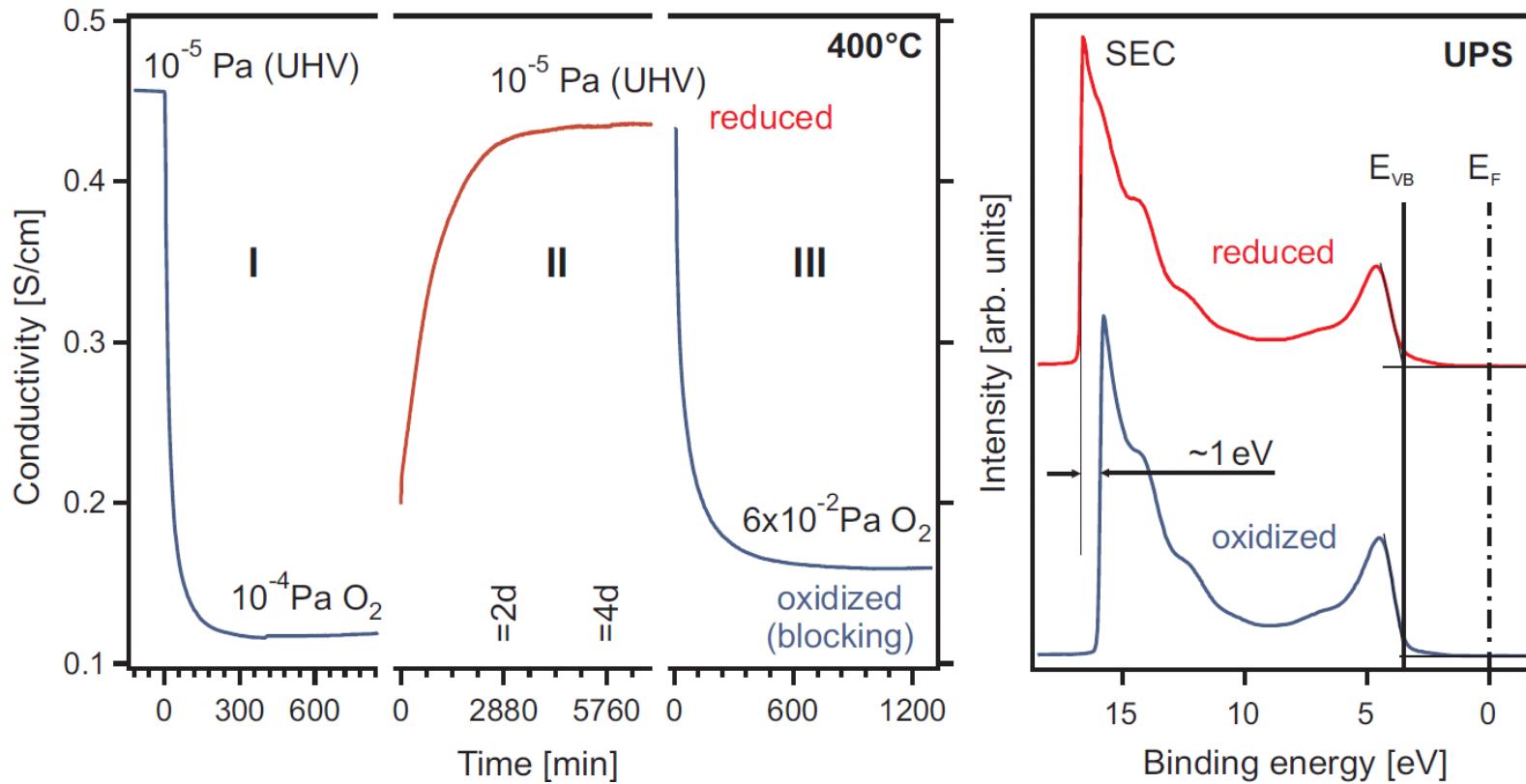
- Almost no change of  $\sigma$  with  $p\text{O}_2$  at 400°C
- Equilibrium carrier concentration not achieved

# Surface modification



➤ Exchange at  $\text{SnO}_2$  possible with 1nm  $\text{In}_2\text{O}_3$  on surface

# Relaxation at low pressure

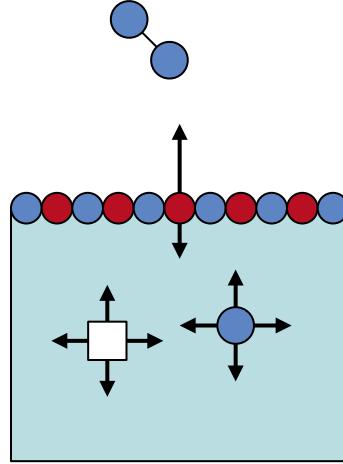


- Relaxation observed when starting from reduced surface
- Oxidation of surface faster than oxidation of bulk

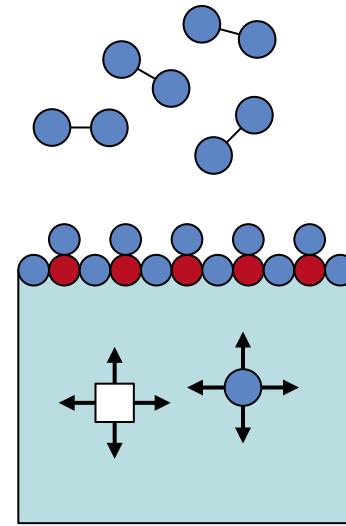
# Oxygen exchange of SnO<sub>2</sub>



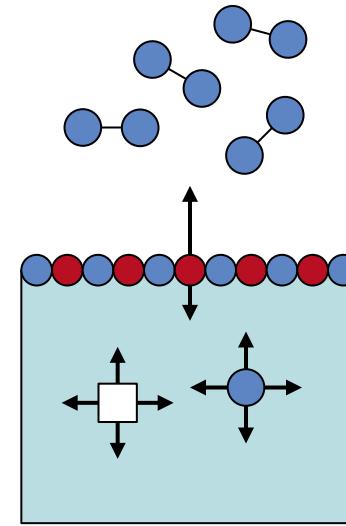
reduced-SnO<sub>2</sub>



oxidized-SnO<sub>2</sub>



SnO<sub>2</sub>/In<sub>2</sub>O<sub>3</sub>



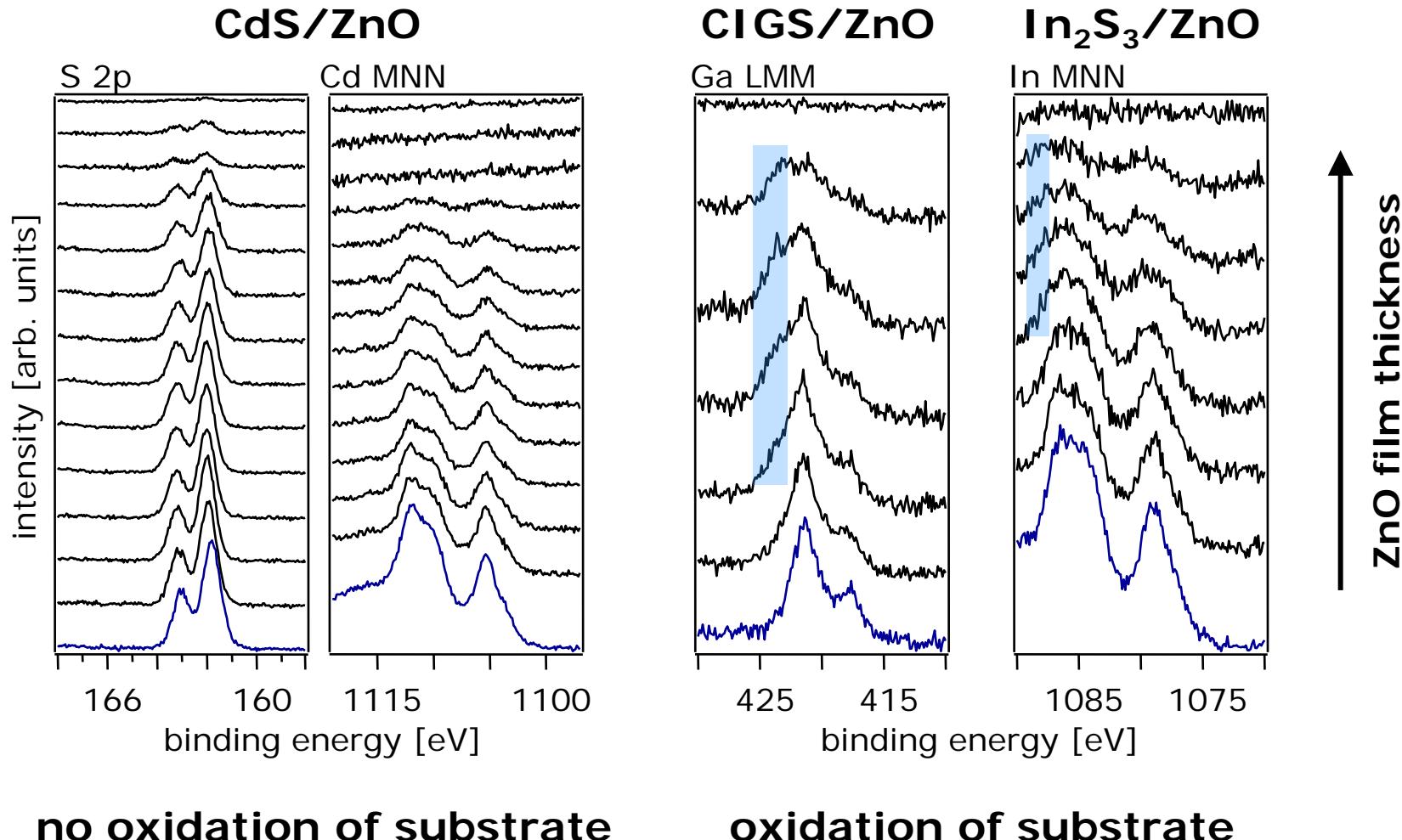
➤ Surface termination is important for oxygen exchange



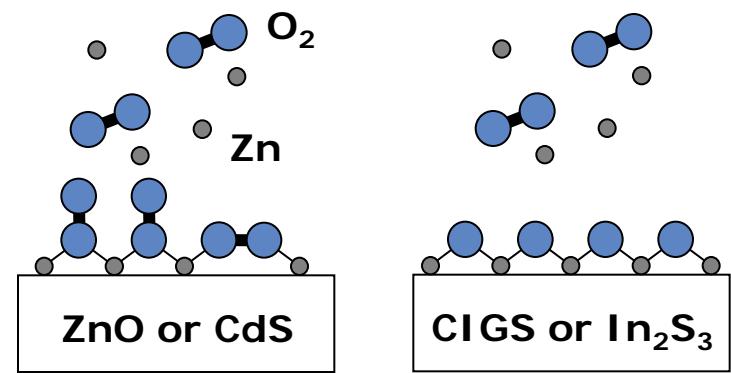
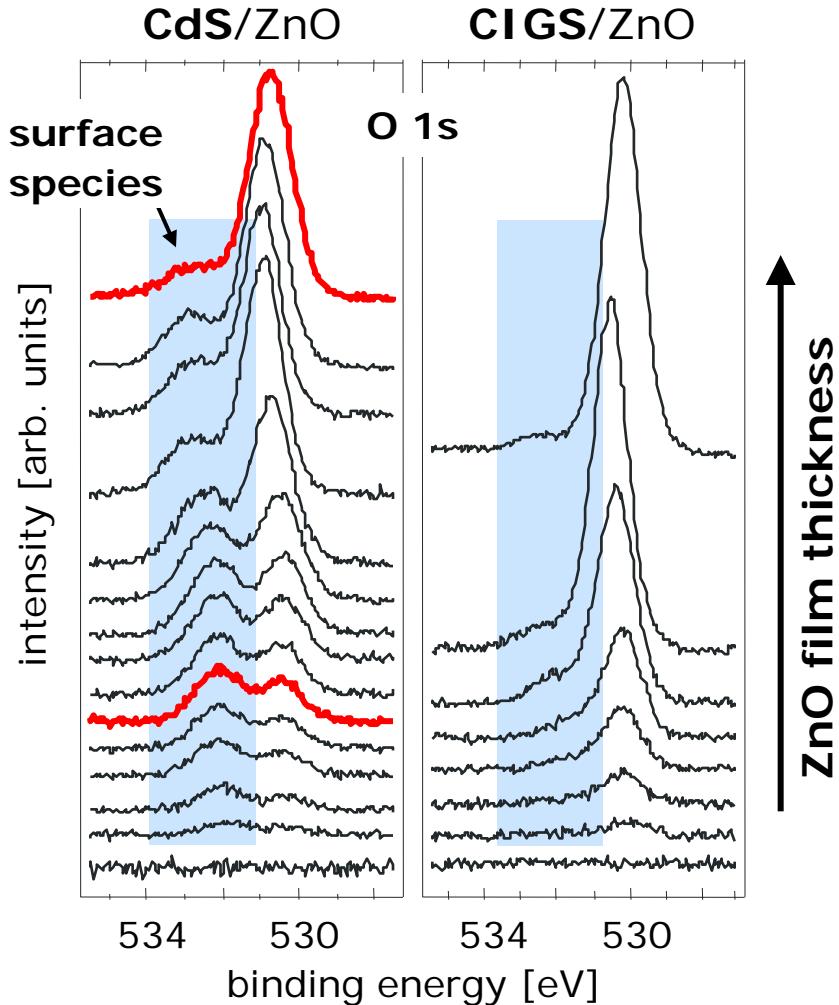
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# Interface Formation

# CdS/ZnO – substrate oxidation



# CdS/ZnO – initial growth



dissociation of  
 $\text{O}_2$  **not** possible

**non-reactive**

dissociation of  
 $\text{O}_2$  possible

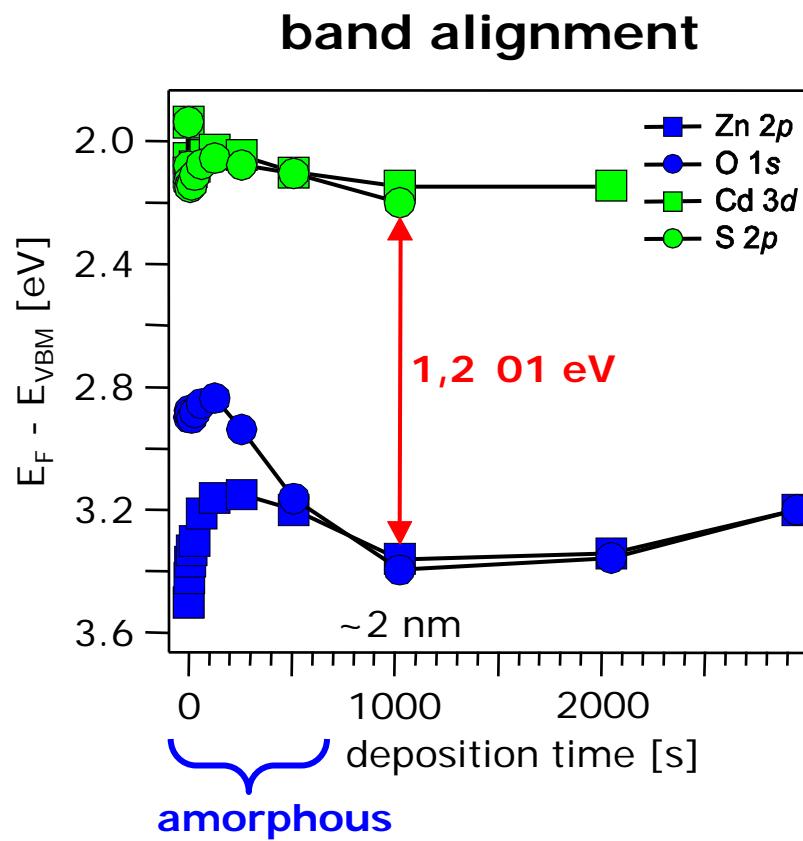
**reactive**

➤ **catalytic activity of  
surface responsible for  
substrate oxidation**

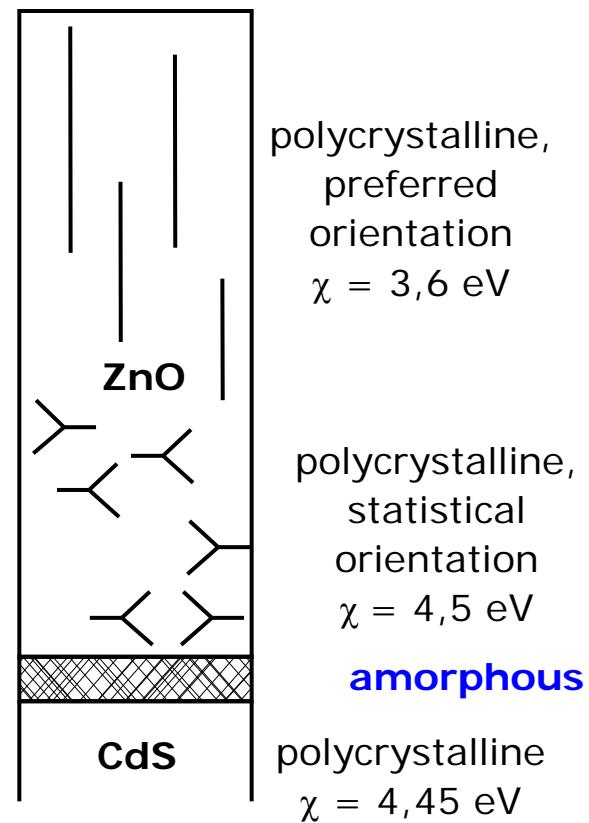
# CdS/ZnO – interface properties



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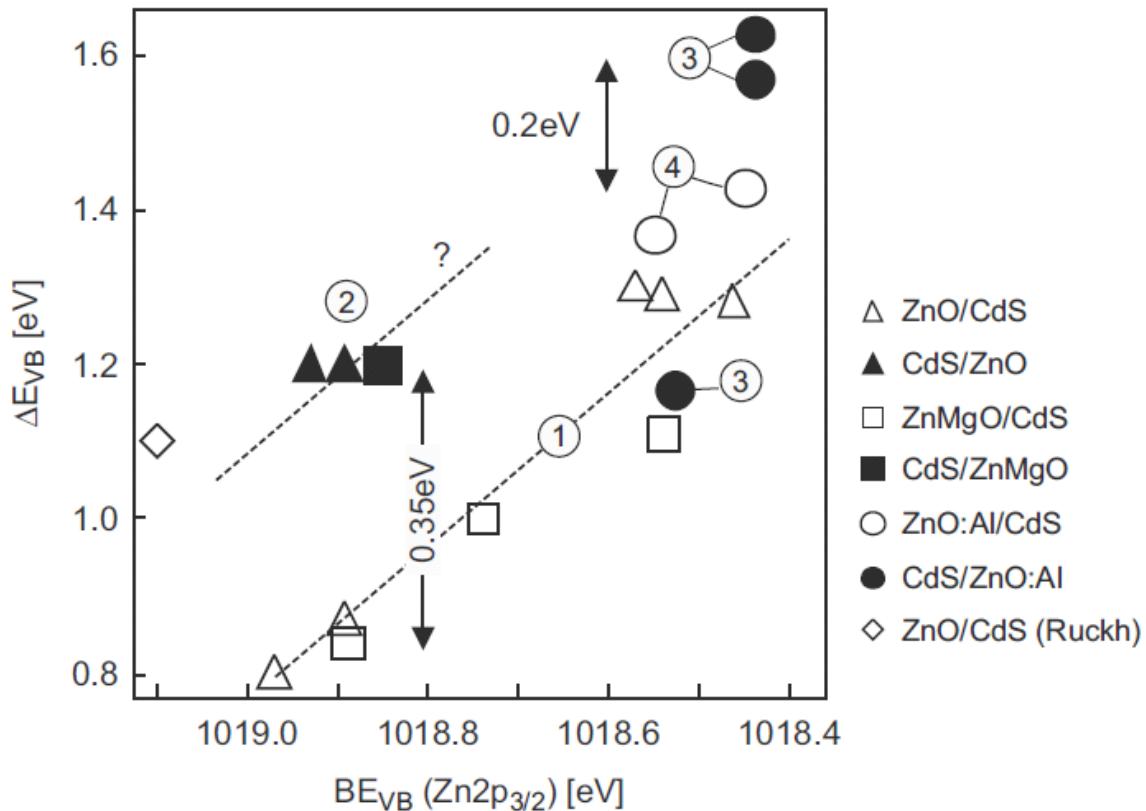


### microstructure



Venkata Rao et al., Appl. Phys. Lett. **87** (2005), 032101.

# CdS/ZnO band alignment



**Large variation of band alignment**

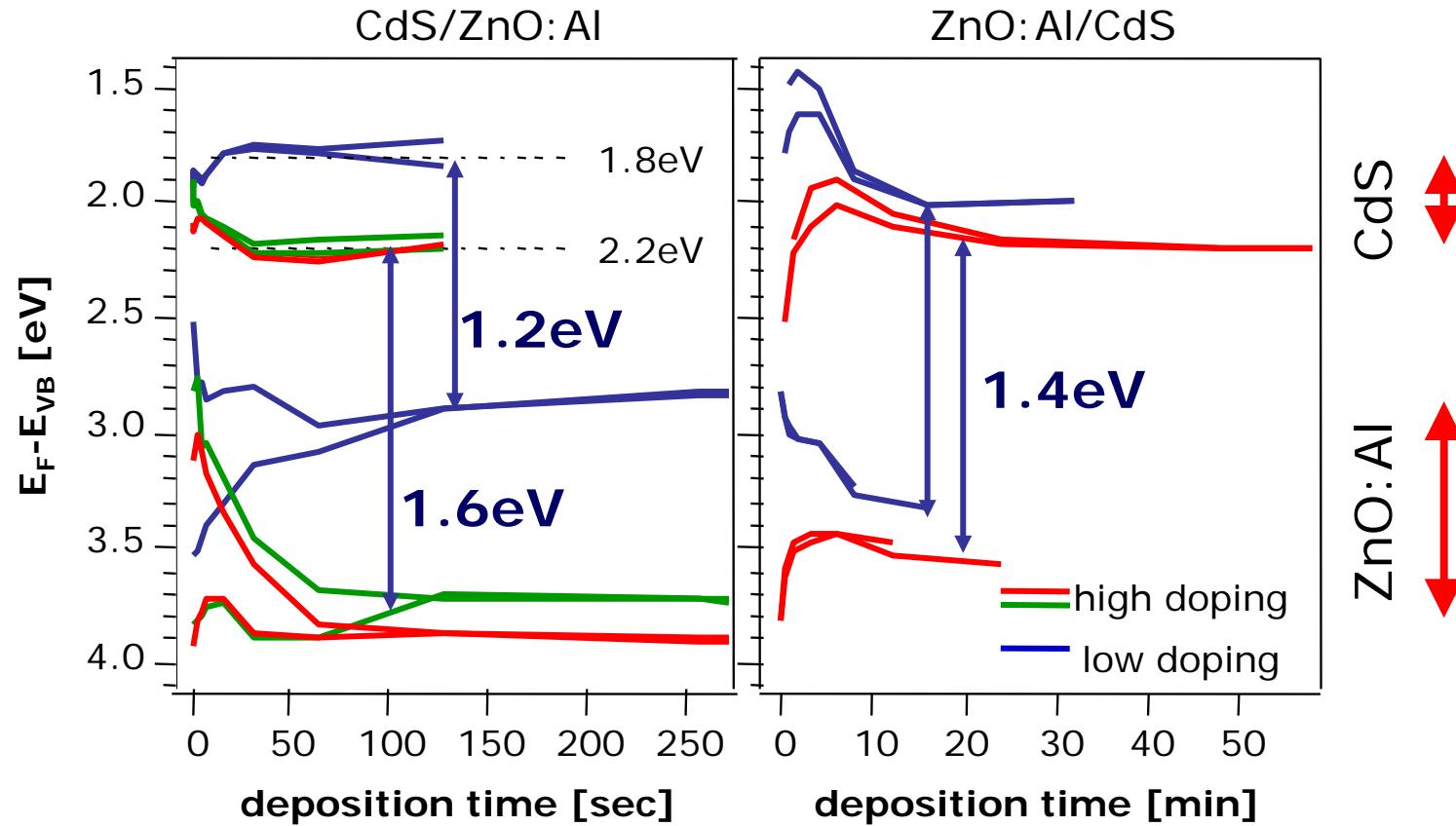
**$\Delta E_{VB}$  depends on**

- Deposition sequence
- ZnO dep. temperature
- **ZnO doping**

details explained in:

Ellmer, Klein, Rech *Transparent Conductive Zinc Oxide* (Springer, 2008), chap 4

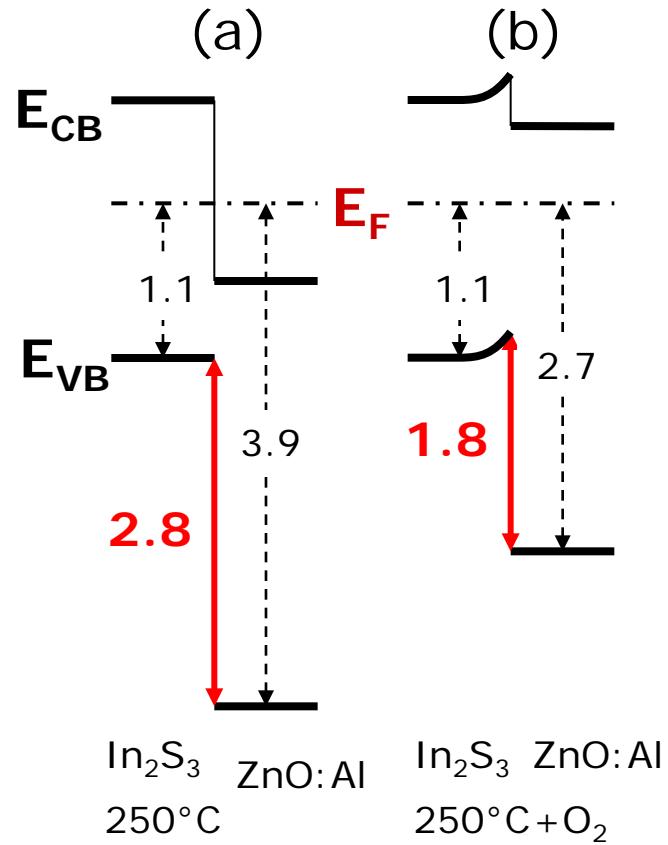
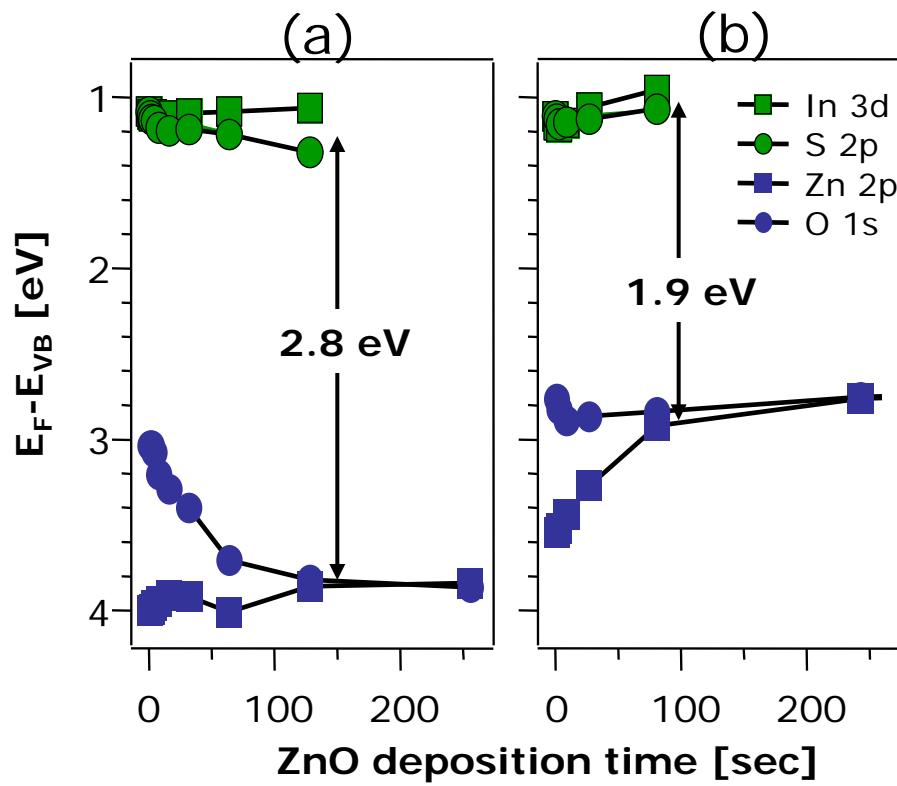
# CdS/ZnO Fermi level pinning



**Fermi level in CdS substrate restricted to  $2.0 \pm 0.2$  eV**

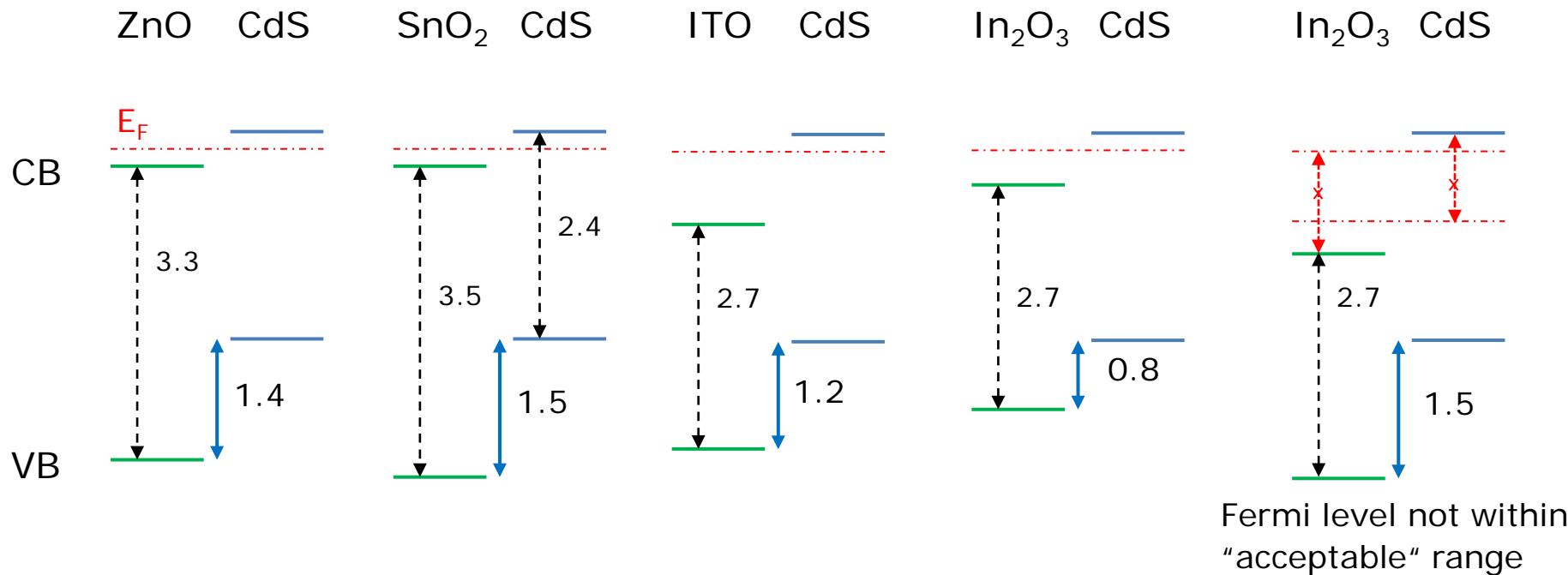
Ellmer, Klein, Rech *Transparent Conductive Zinc Oxide* (Springer, 2008), chap 4

# In<sub>2</sub>S<sub>3</sub>/ZnO Fermi level pinning



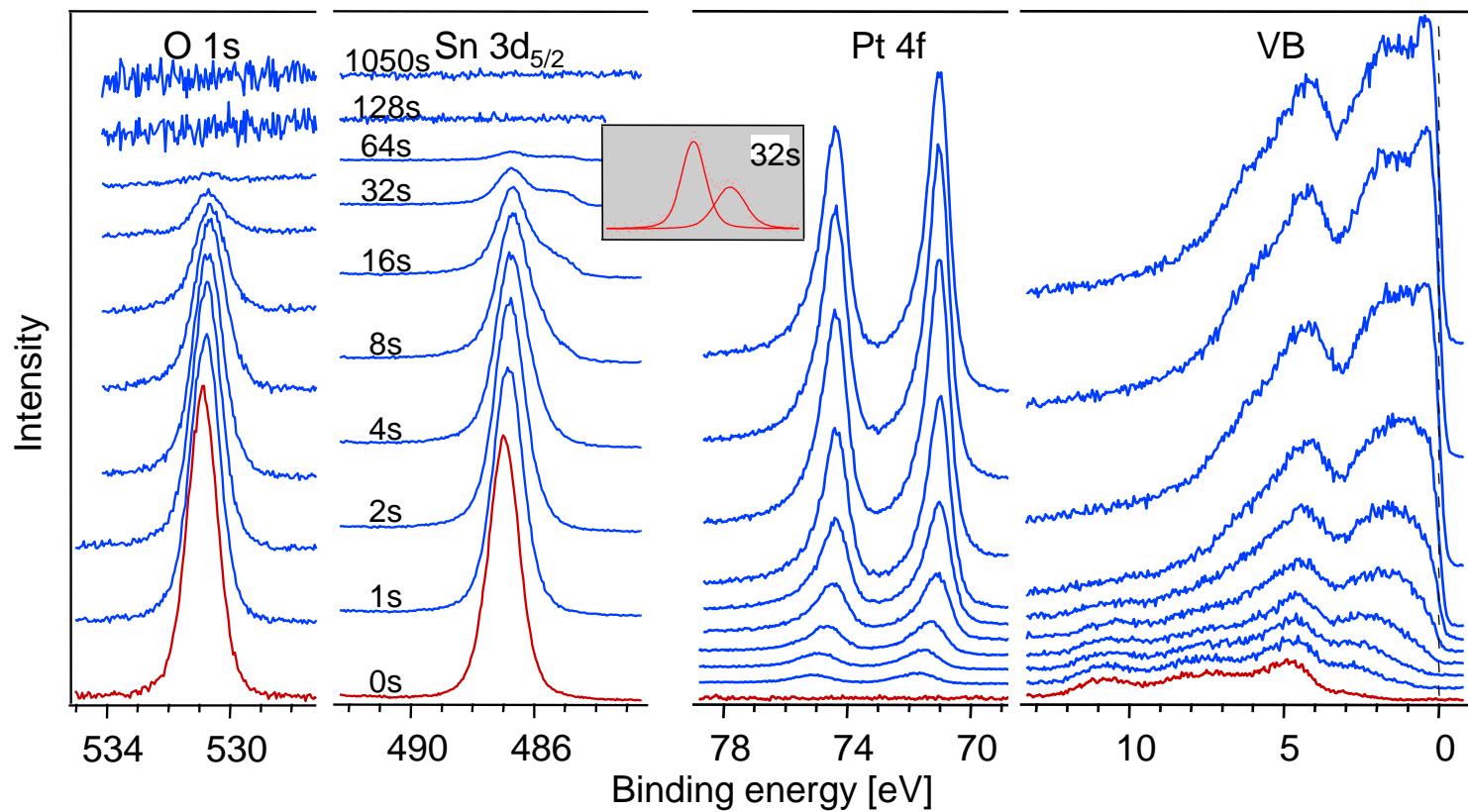
- No band bending in In<sub>2</sub>S<sub>3</sub> and ZnO
- Band alignment defined by doping levels

# TCO / CdS – band alignment



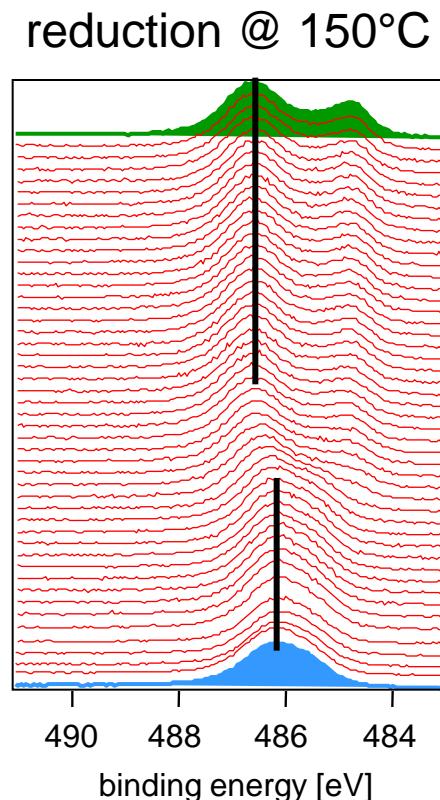
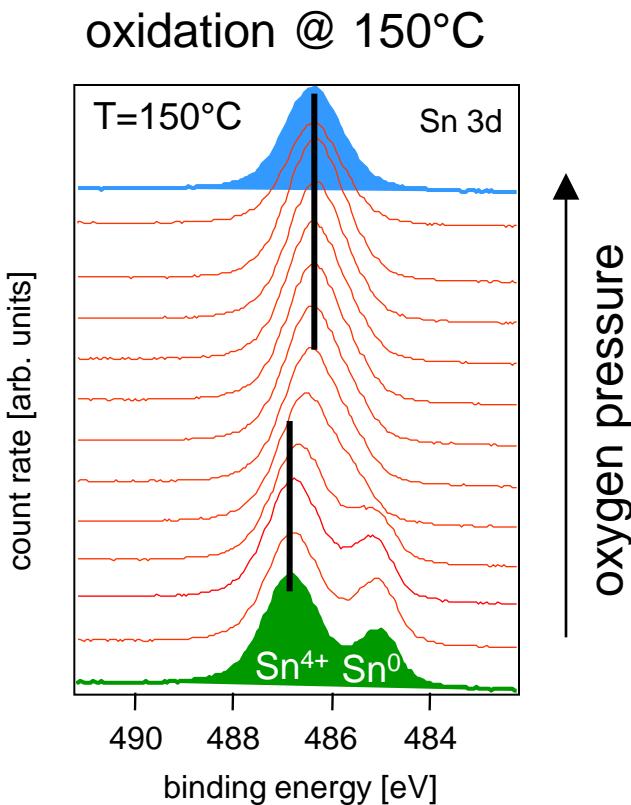
- Valence band maxima of TCOs at comparable energy  
**but:** Band alignment influenced by TCO gap and doping  
due to Fermi level pinning in CdS

# SnO<sub>2</sub>/Pt – interface formation



**Reduction of SnO<sub>2</sub> during deposition**

# $\text{SnO}_2/\text{Pt}$ – interface chemistry



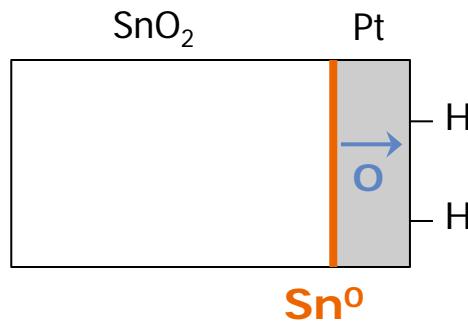
- 150°C:  $\text{Sn}^0 \leftrightarrow \text{Sn}^{4+}$  with intermediate  $\text{Sn}^{2+}$  state
- 100°C:  $\text{Sn}^0 \leftrightarrow \text{Sn}^{2+}$
- Oxidation/reduction not observable for
  - large Pt islands
  - bare  $\text{SnO}_2$  surface

Reversible oxidation/reduction of Sn

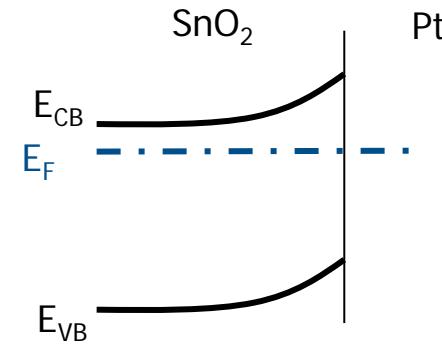
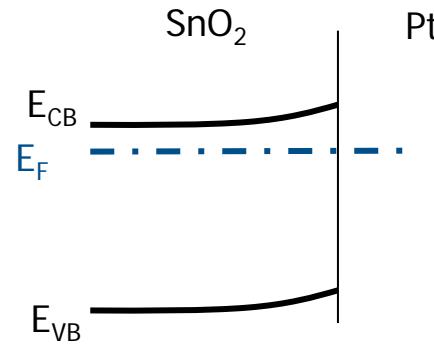
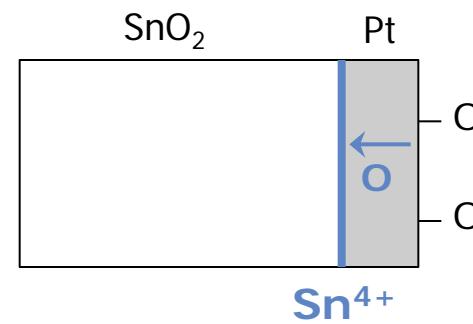
# Chemistry at buried interface



Reducing environment



Oxidizing environment



Oxygen is reversibly transported to/from the interface

# Summary



- Work functions depend on doping, surface orientation ( $\text{ZnO}$ ,  $\text{In}_2\text{O}_3$ ,  $\text{SnO}_2$ ?) and surface termination ( $\text{In}_2\text{O}_3$ ,  $\text{SnO}_2$ )
- Oxygen exchange generally possible for  $\text{In}_2\text{O}_3$  but can be suppressed at stoichiometric  $\text{SnO}_2$  surfaces
- Reactivity of interfaces determined by catalytic activity of surface for dissociation of oxygen
- Energy band alignment characterized by similar valence band energies but may be affected by Fermi level pinning
- Schottky barrier heights can depend on oxygen pressure

# Thanks



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- **Frank Säuberlich, Yvonne Gassenbauer, Christoph Körber, André Wachau, Mareike Hohmann, Karsten Rachut (Surface Science)**
- **Paul Erhart, Péter Ágoston, Karsten Albe (Materials Modelling)**
- **S.P Harvey, T.O. Mason (Northwestern University)**
- **BMBF (ZnO), DFG (SFB 595), DFG-NSF (Materials World Network)**